



Center for Energy Efficient
Electronics Science

Synthesis and characterization of 2D Materials *towards Energy Efficient Electronics*

Pin-Chun Shen, Jing Kong (MIT)

E3S Seminar

December 6, 2017

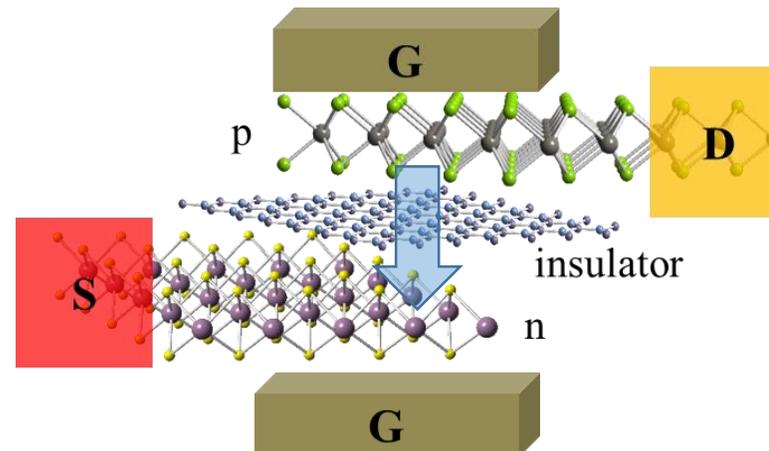
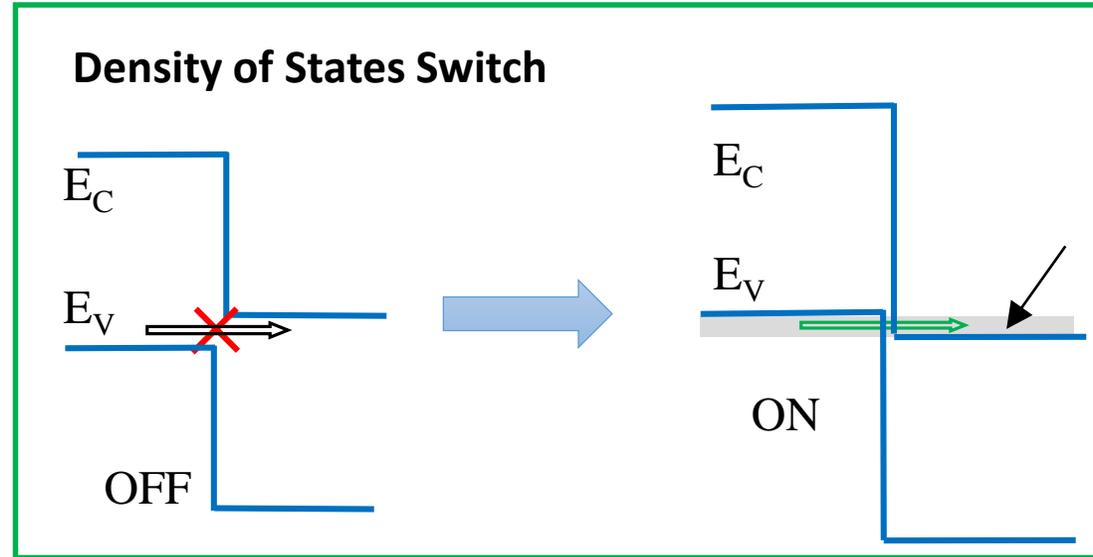
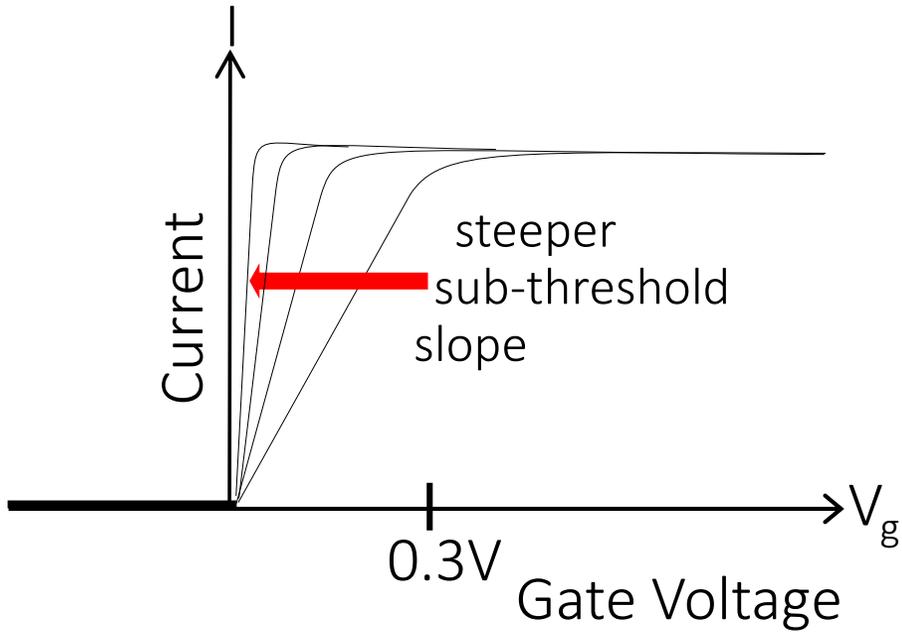
Collaborators: Eli Yablonovitch, Ali Javey, David Zulia, Jeff Bokor



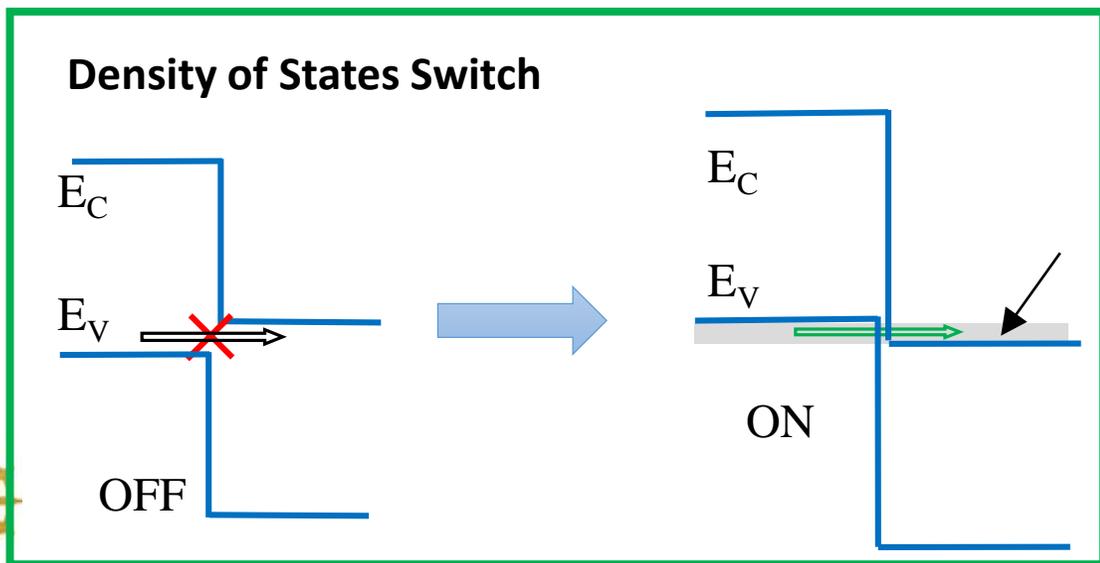
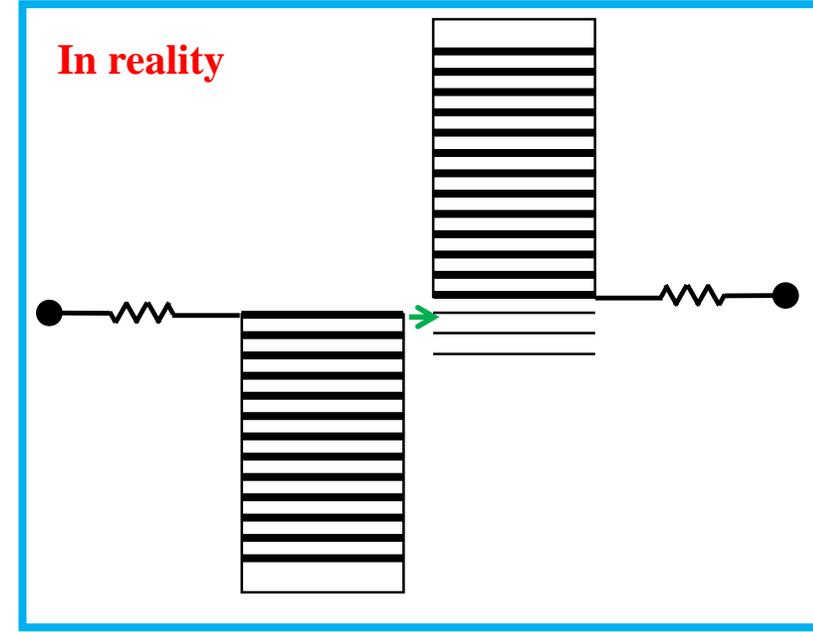
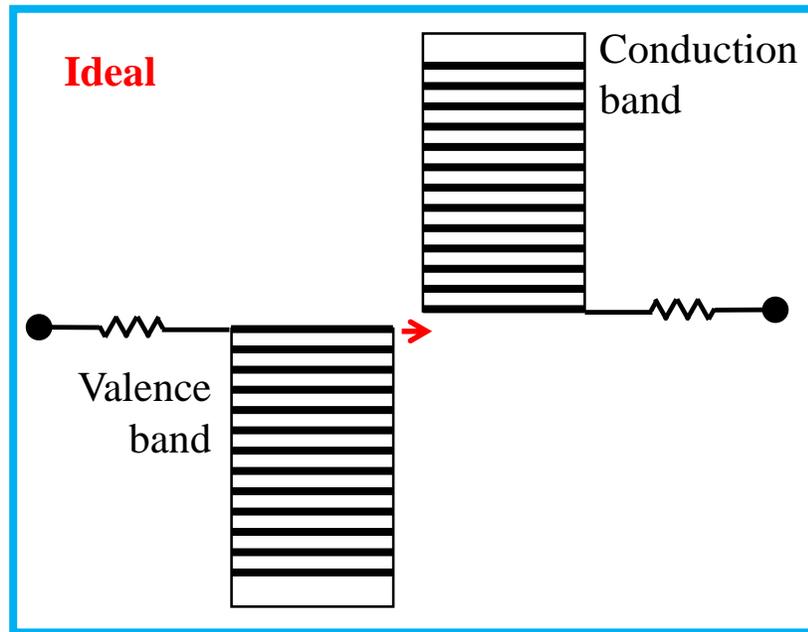
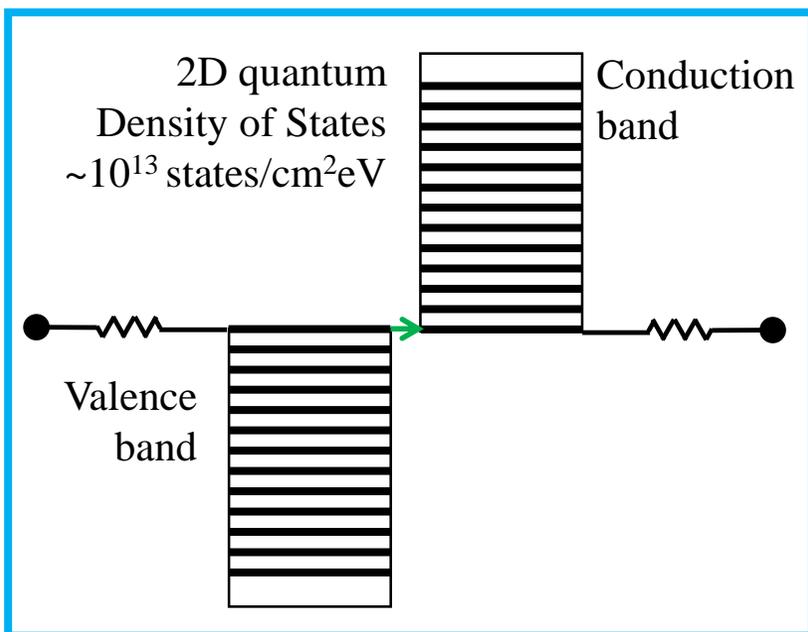
*A Science
& Technology
Center*



Tunnel Transistors As a More Sensitive Electronic Switch

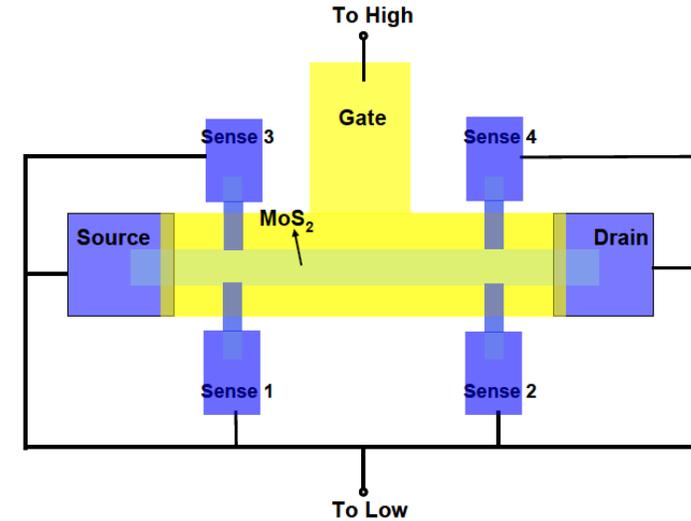
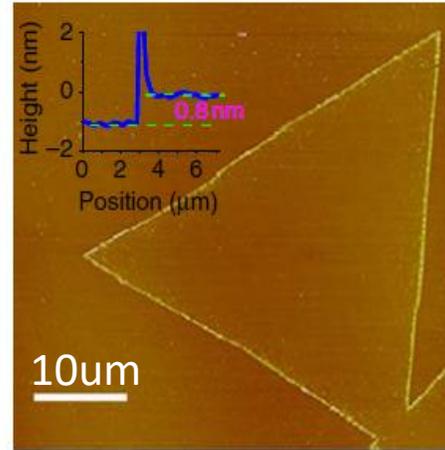
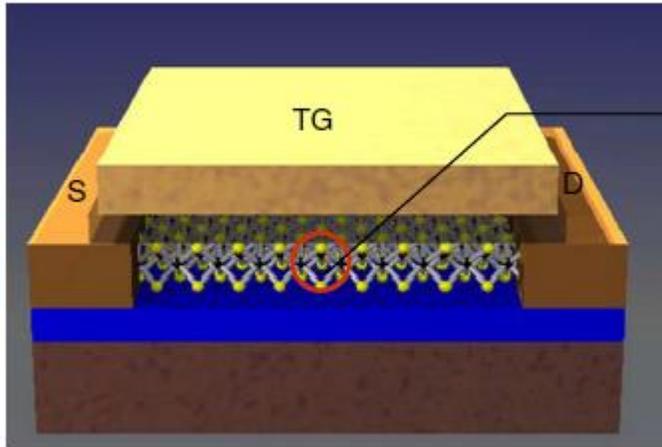


Tunnel Transistors As a More Sensitive Electronic Switch



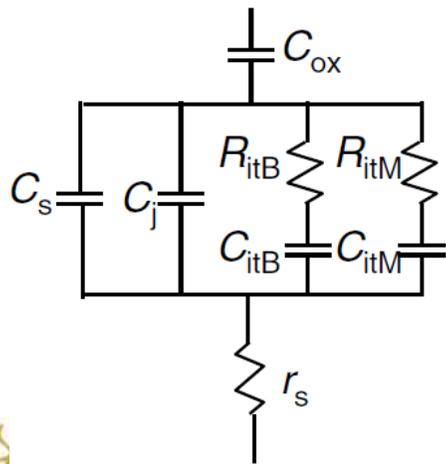
Can we achieve 2D materials with 2D interface defect density $\ll 10^{12}$ states/cm²eV?

D_{it} Through Capacitance and AC Conductance Measurements



W. Zhu et. al, **Nat. Comm.** DOI: 10.1038/ncomms4087 (2014)

Device model:



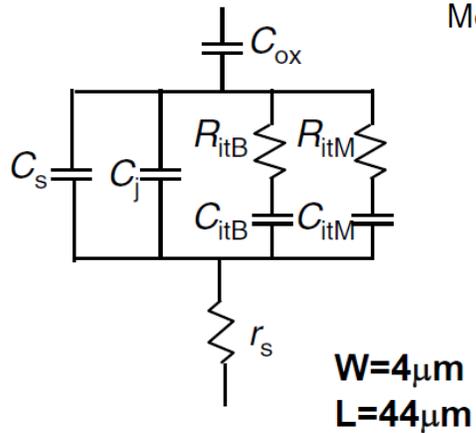
$$Z = (Y_{itB} + Y_{itM} + i\omega C_s + i\omega C_j)^{-1} + (i\omega C_{ox})^{-1} + r_s \quad C_{ms} = -\frac{1}{\omega * \text{Im}[Z]}$$

- C_s : the quantum capacitance, C_j : the parasitic capacitance, C_{ox} : the oxide capacitance, r_s : the series resistance
- Y_{itM} and Y_{itB} : admittance of the traps
 $(Y_{itB} = [\tau_{itB}/C_{itB} + 1/(i\omega C_{itB})]^{-1})$

D_{it} Through Capacitance and AC Conductance Measurements

Device model:

$$Z = (Y_{itB} + Y_{itM} + i\omega C_s + i\omega C_j)^{-1} + (i\omega C_{ox})^{-1} + r_s$$

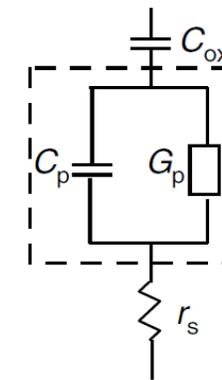


Measurement model:

$$C_{ms} = -\frac{1}{\omega * \text{Im}[Z]}$$

○ ○ Extracted from C_{ms}
 □ Extracted from G_p
 — — Model

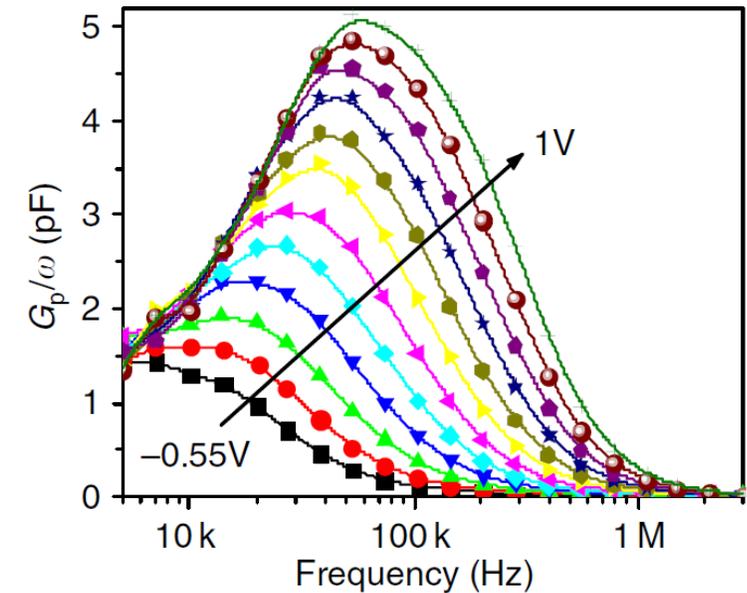
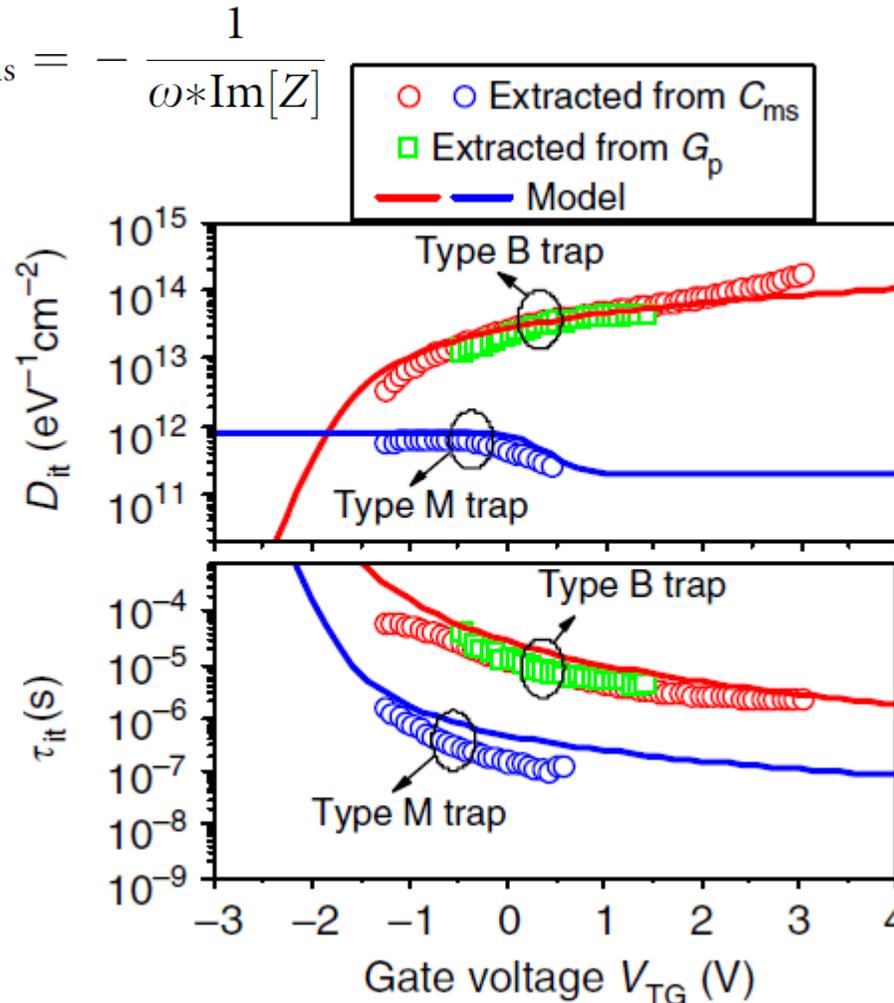
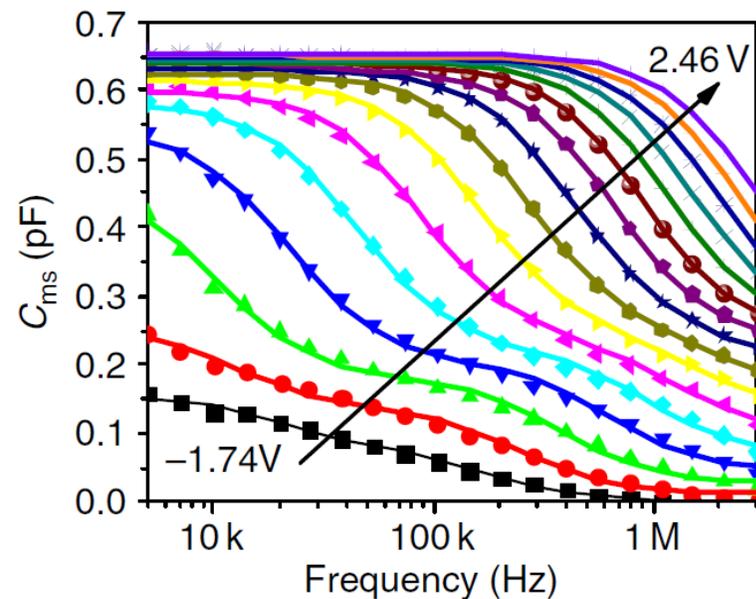
Parallel model:



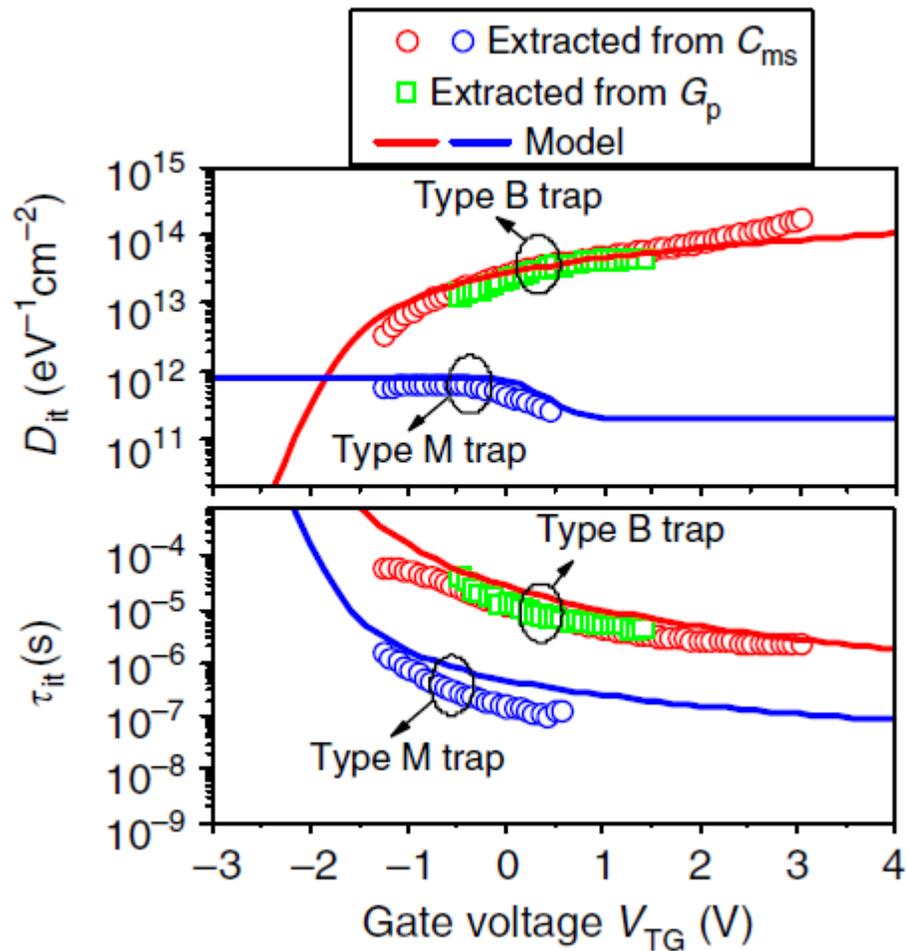
$$\frac{G_p(\omega)}{\omega} = \frac{eD_{itB}}{2\omega\tau_{itB}} \ln[1 + (\omega\tau_{itB})^2]$$

$$D_{itB} = \frac{2.5}{e} \left(\frac{G_p}{\omega} \right)_{\text{peak}}$$

$$\tau_{itB} = \frac{1.98}{2 \times 3.14 \times f_0}$$



D_{it} Through Capacitance and AC Conductance Measurements



$$D_n(E) = \begin{cases} \alpha D_0 \exp\left[\frac{E-E_D}{\varphi}\right] + D_{itM}, & E_D - \frac{1}{2}E_G < E < E_D \\ D_0 - (1-\alpha)D_0 \exp\left[-\frac{E-E_D}{\varphi'}\right] + D_{itM}, & E > E_D \end{cases}$$

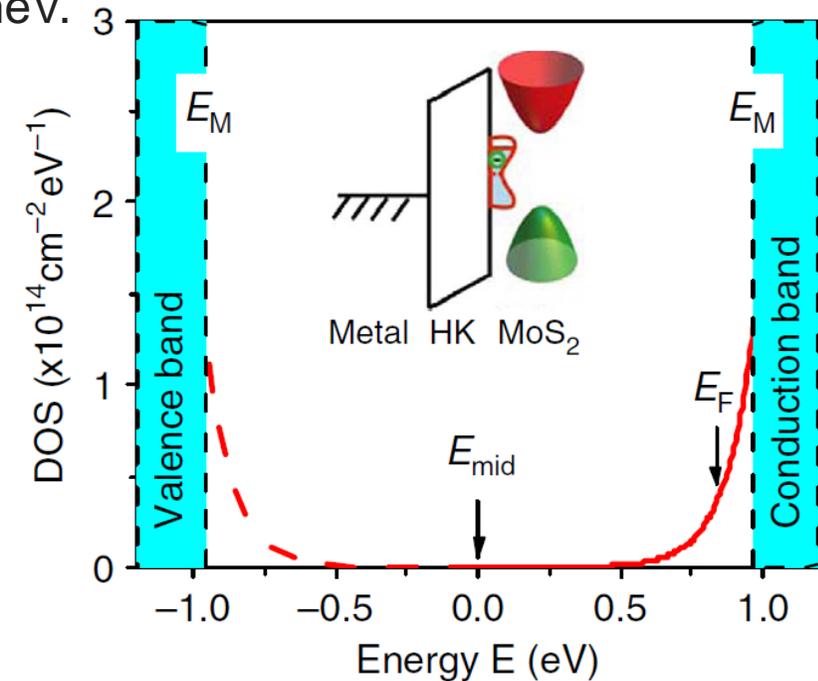
D_0 : $3.3 \times 10^{14} \text{ eV}^{-1}\text{cm}^{-2}$ (the 2D density-of-states for MoS₂)

φ : the characteristic energy width of the band tail

φ' is chosen so that the two piece-wise functions have continuous gradients at E_D

Best fit $\alpha=0.33$ and $\varphi = 100 \text{ meV}$.

- band tail states follow an exponentially decaying behavior
- a significantly large energy width of 100 meV



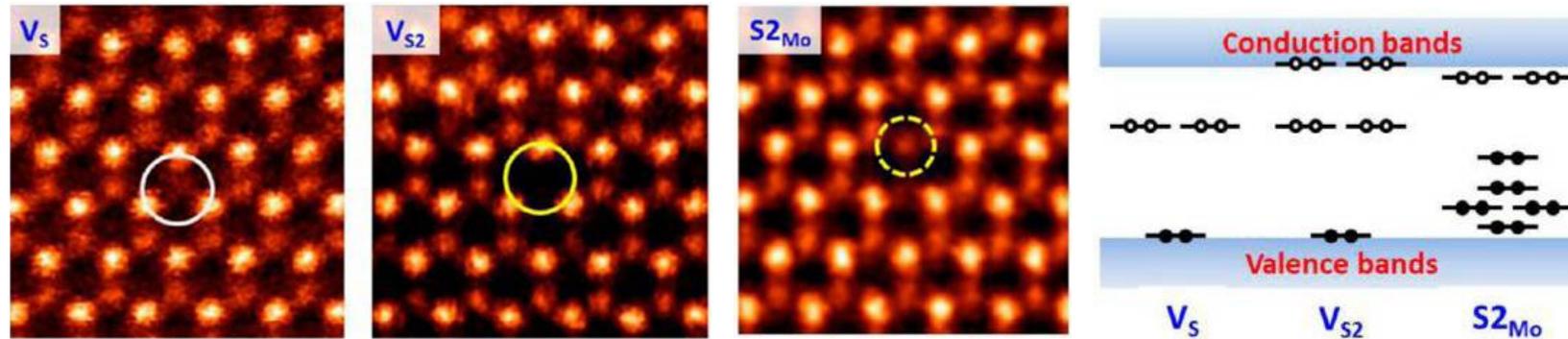
Improving from previous results

- Understanding of the microscopic origin of these trap states is critical for further improvement of the material's electronic properties
 - Contribution from the substrate, processing:
 - hBN substrate vs. SiO₂
 - Transfer process
 - Intrinsic materials quality
 - Characterization /correlation
 - Improve on the synthesis process

Goal: High quality 2D materials with low defect densities

- Defect characterization

- Various types of defects and characterization development
- Contribution to defect states



W. Zhou et. al, **Nano Letters** 13, 2615-2622, (2013)

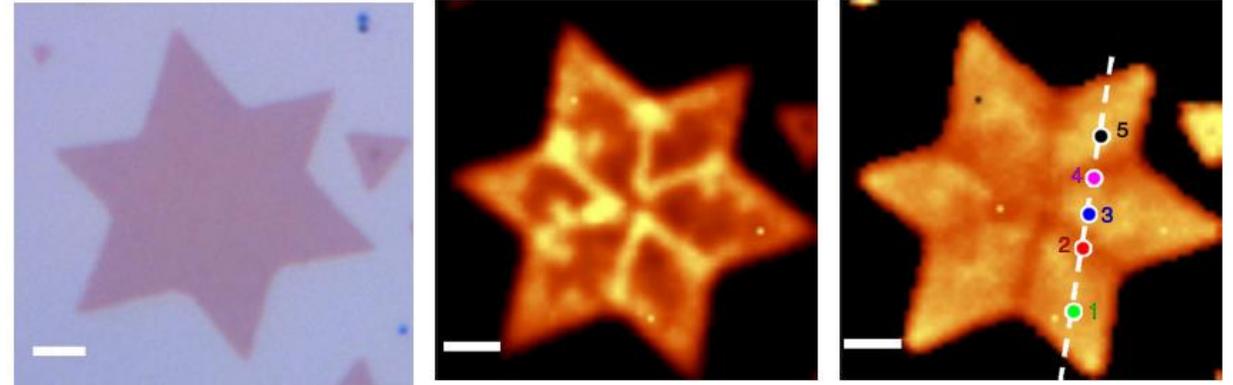
- Defect traps states characterization

- C-V and D_{it} measurement
- Correlation with device characteristics: mobility, contact resistance
- Correlation with optical characteristics?

MoS2 will be used as a model system
Work in Progress!

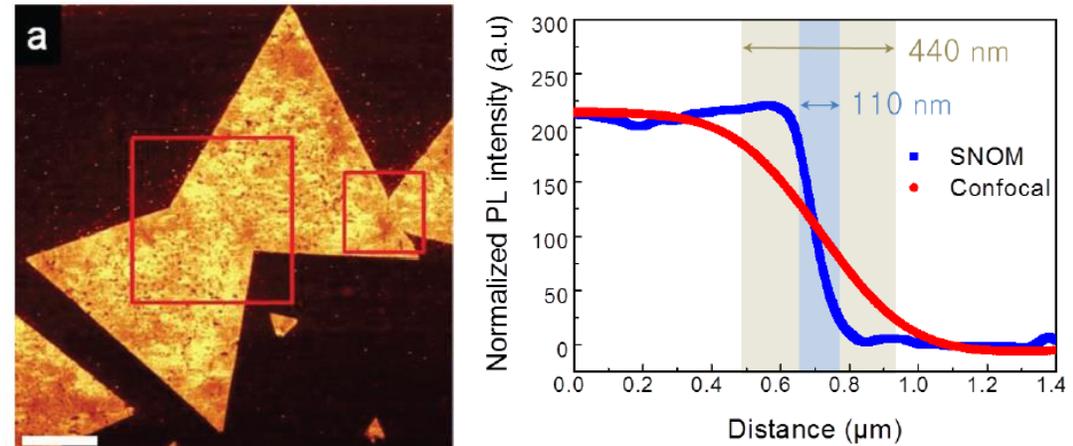
Grain boundary defect characterization

- Photoluminescence mapping (Intensity, peak position): 440nm resolution



Z. Liu et. al, **Nat. Comm** 5, 5346 (2014)

- SNOM PL mapping: 110nm resolution

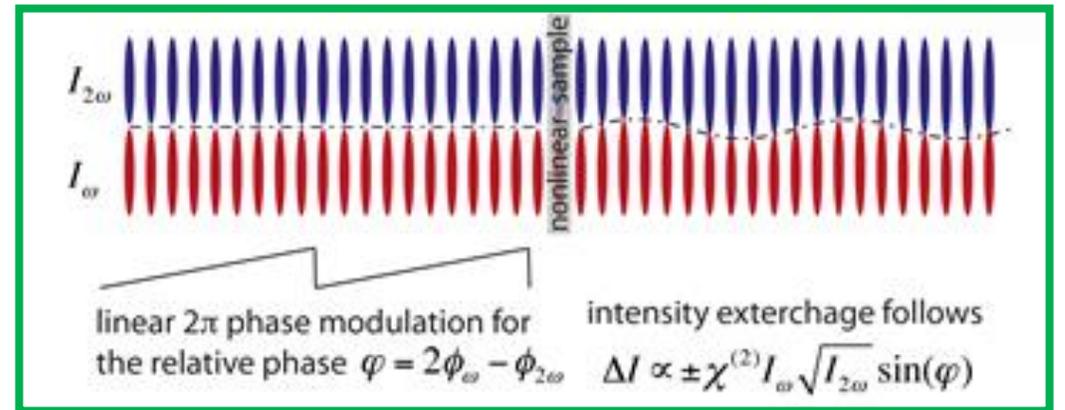
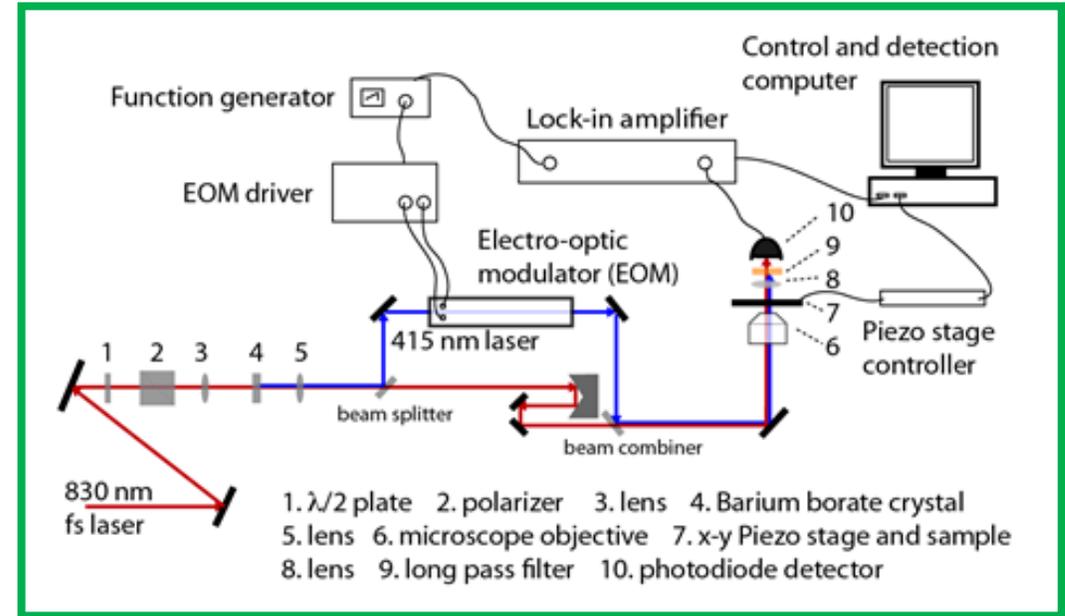


Y. Lee et. al, **Nanoscale** 7, 11909 (2015)

Phase-Modulated Optical Parametric Amplification Imaging



- EOM: modulates the relative optical phase between the two fields (1 MHz to a depth of 2π) according to a saw tooth waveform
- the two fields exchange intensity according to the phase modulation and the sample's nonlinear response
- Advantages over SHG:
 - Much easier
 - No need for single photon detector
 - Normal room lighting
 - Capture phase of the input signal in addition to its magnitude



Y. Gao et. al., manuscript in preparation

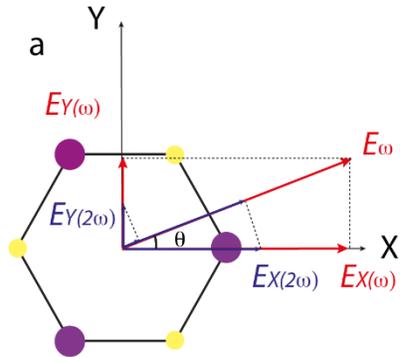
Collaboration with William Tisdale group in Chem E at MIT



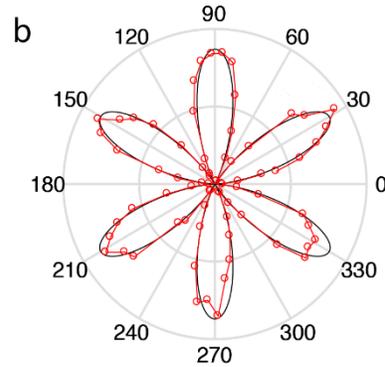
Center for Energy Efficient Electronics Science

MoS₂ Grain Orientation

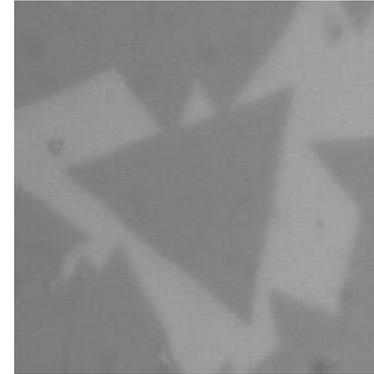
- Second harmonic generation (SHG) in monolayer MoS₂



$$E_{\wedge}^{2W} \propto \mu - c_{xxx} \sin 3q$$

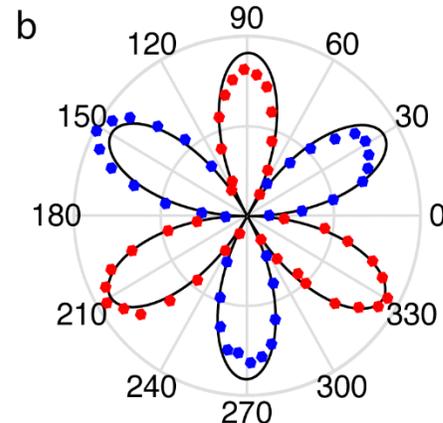
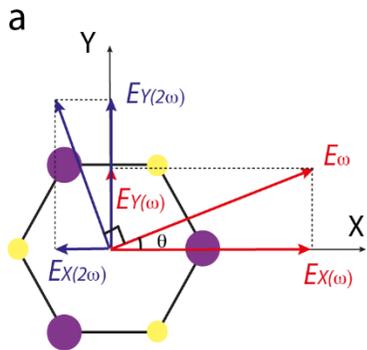


$$I_{\wedge}^{2W} \propto \mu (c_{xxx} \sin 3q)^2$$

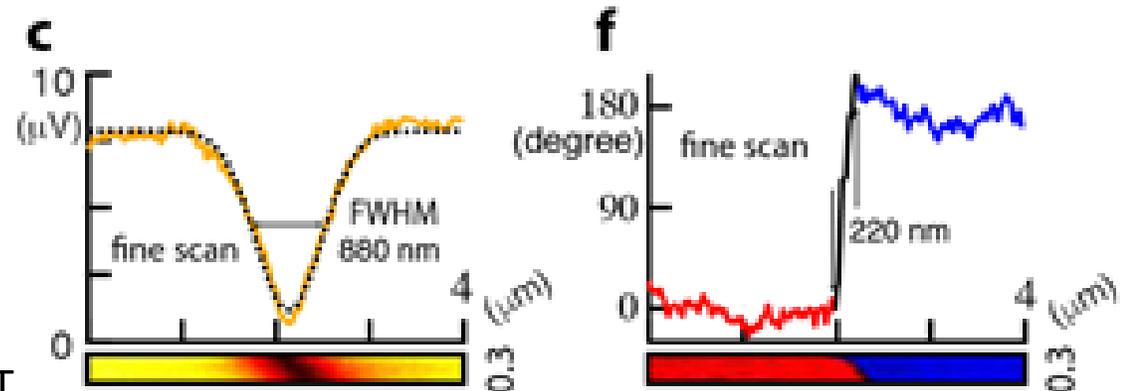
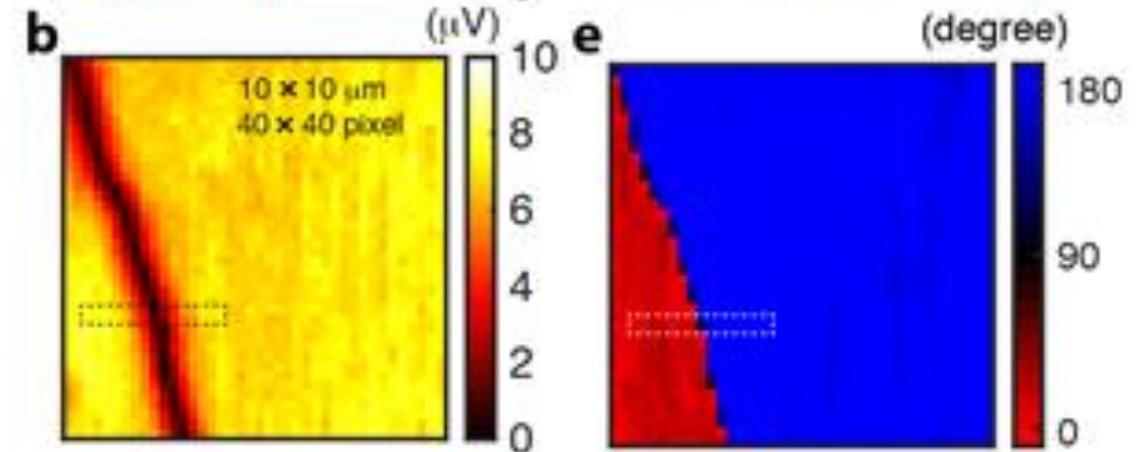
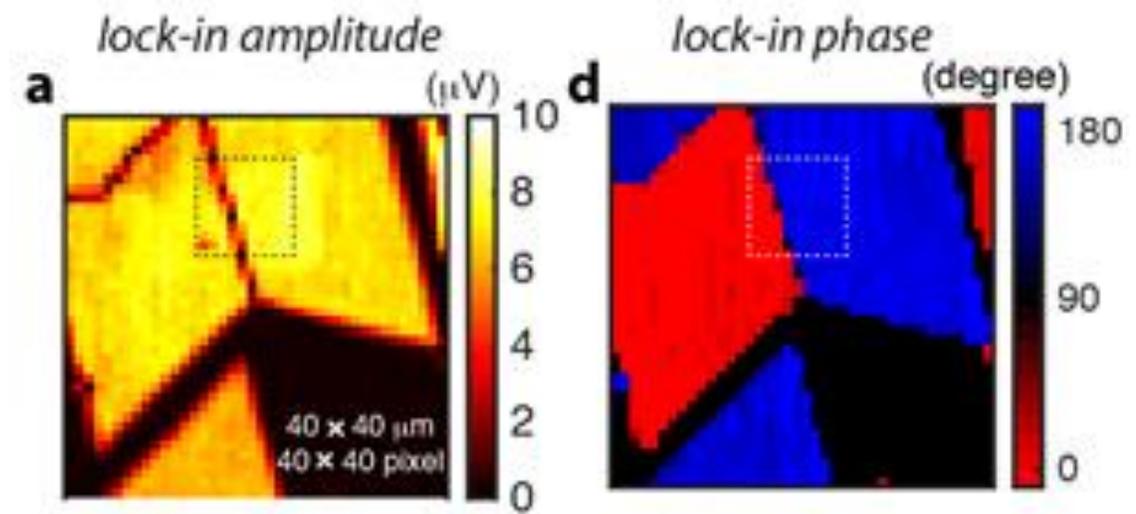
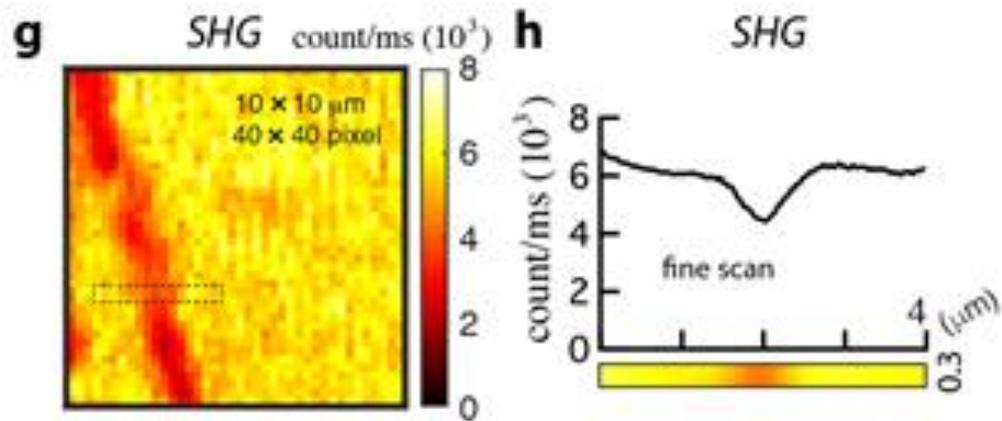
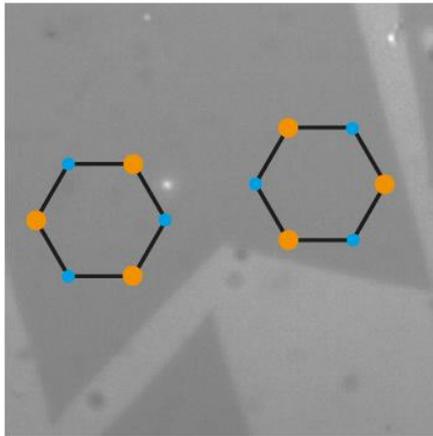


θ : orientation of monolayer MoS₂ triangle relative to the field polarizations

- pOPA signals in monolayer MoS₂

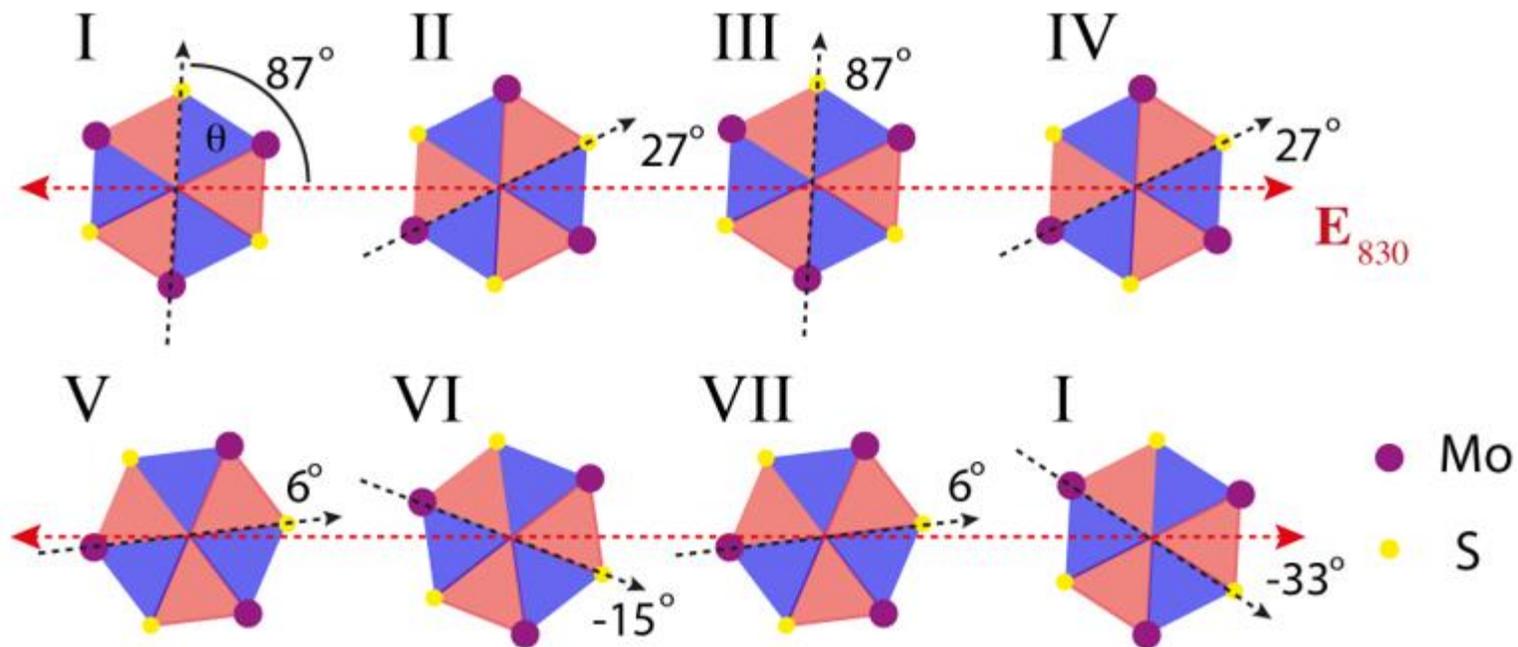
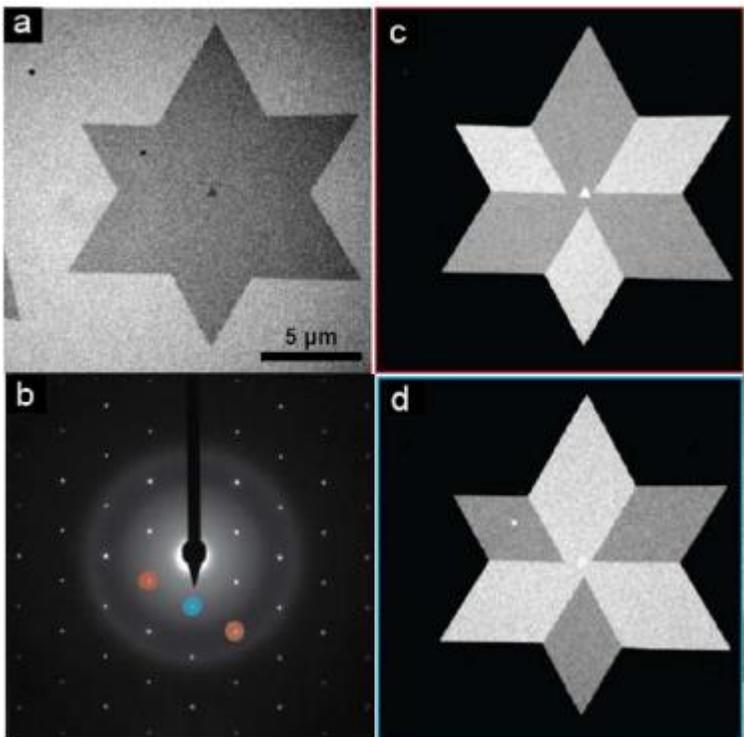


MoS₂ Grain Characterization

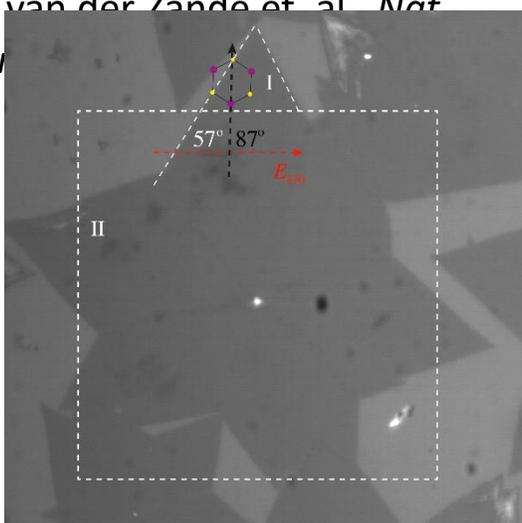


- Grains with mirror symmetry distinguished
- Better contrast and higher resolution

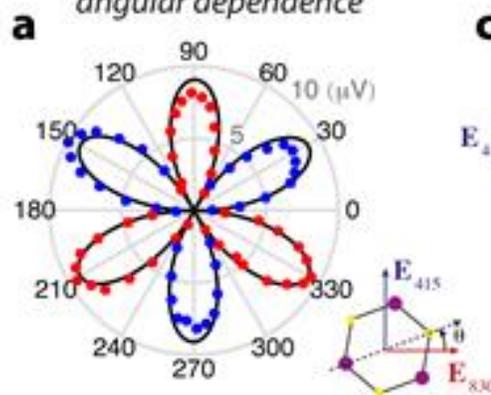
MoS₂ Grain Characterization



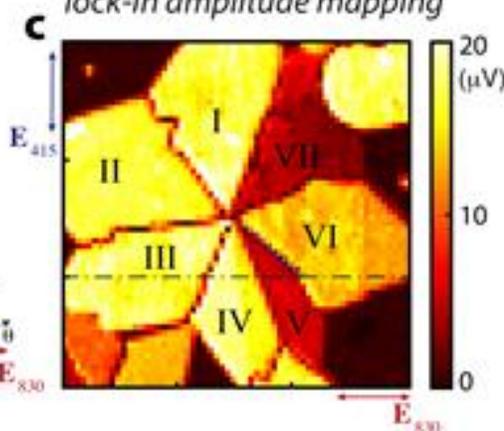
A. M. van der Zande et al. *Nat Mater*



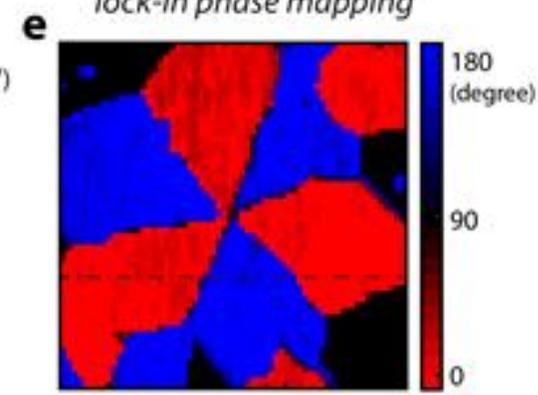
single domain rotation angular dependence



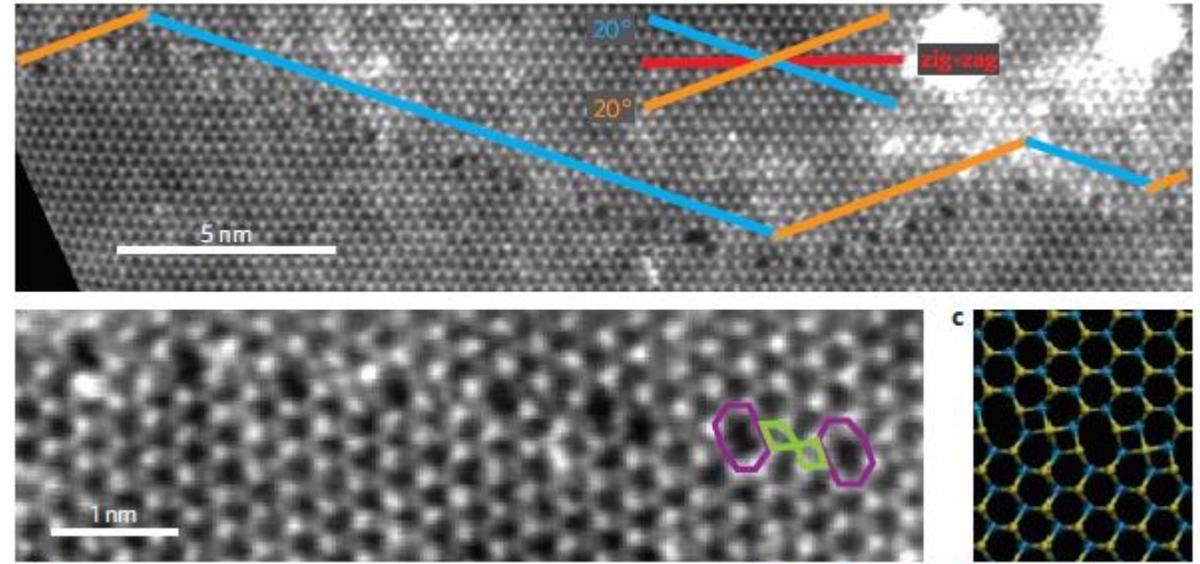
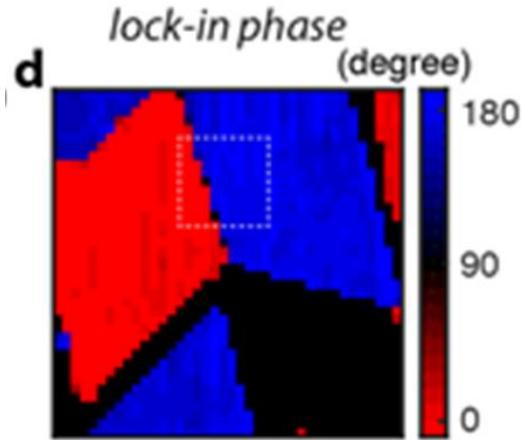
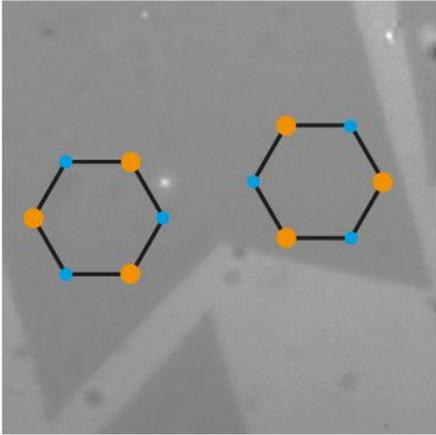
multiple domain lock-in amplitude mapping



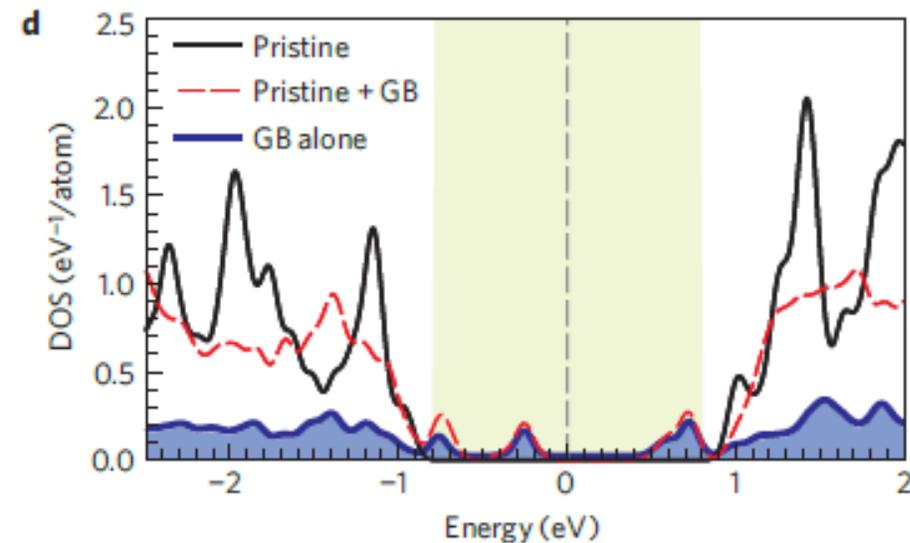
multiple domain lock-in phase mapping



MoS₂ Grain Characterization

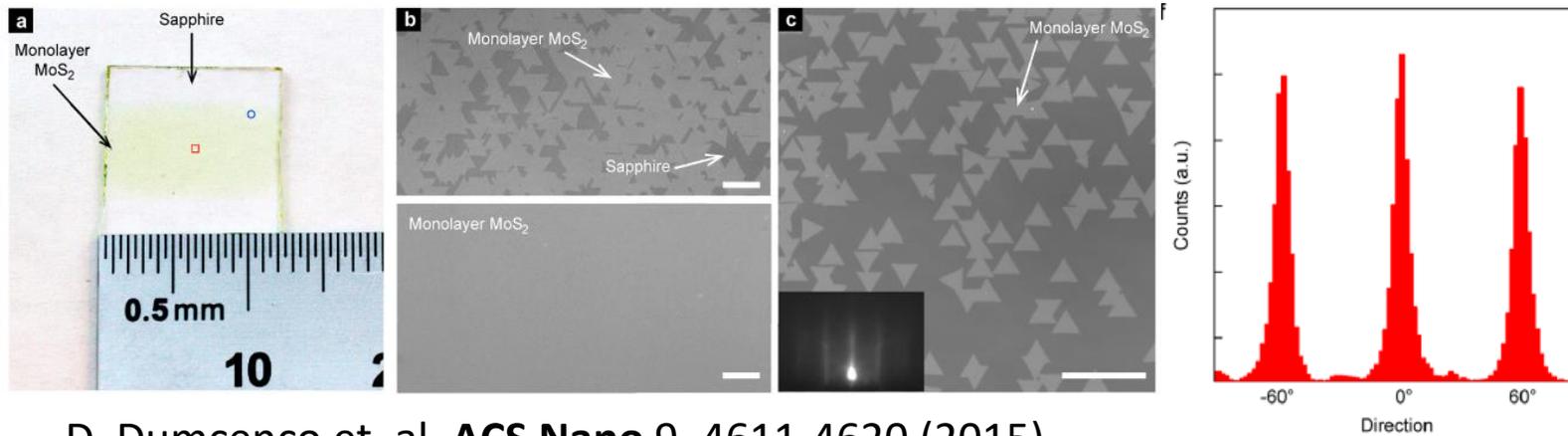


- Various types of grain boundaries contribute to midgap states or even metallic conduction
- Need to avoid these via growth of much larger single crystalline domains



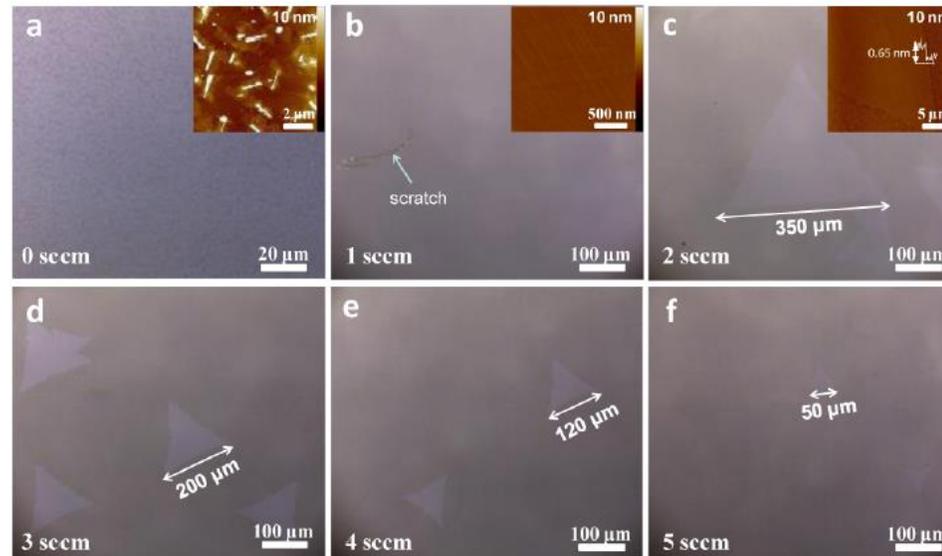
Moving forward: large single crystal grains in MoS₂

- single crystalline Sapphire growth substrate



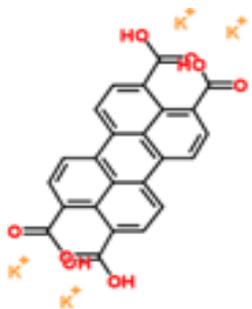
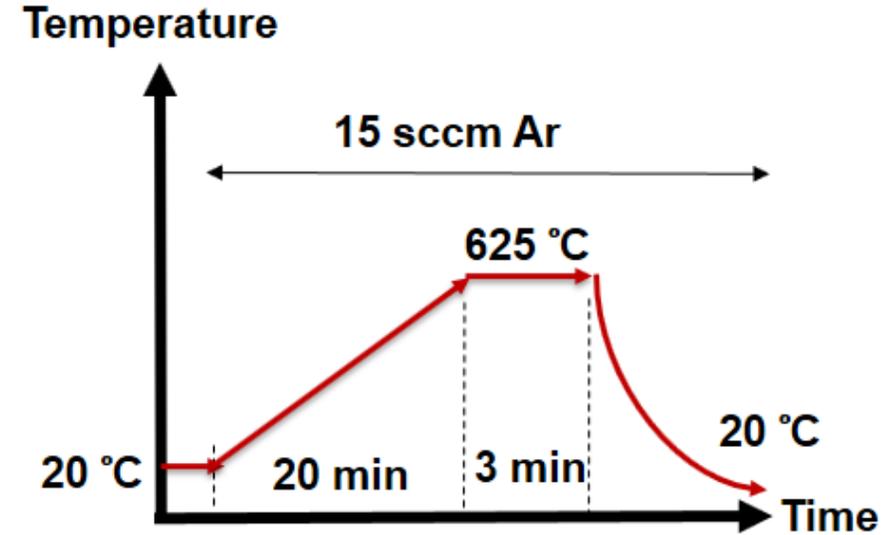
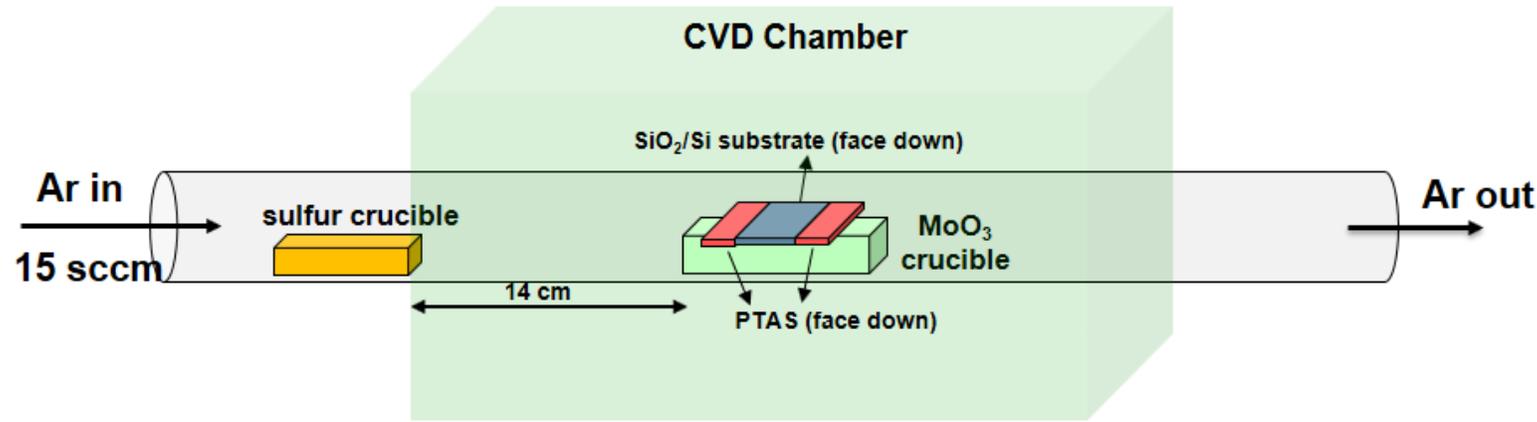
D. Dumcenco et. al, **ACS Nano** 9, 4611-4620 (2015)

- Oxygen assisted CVD

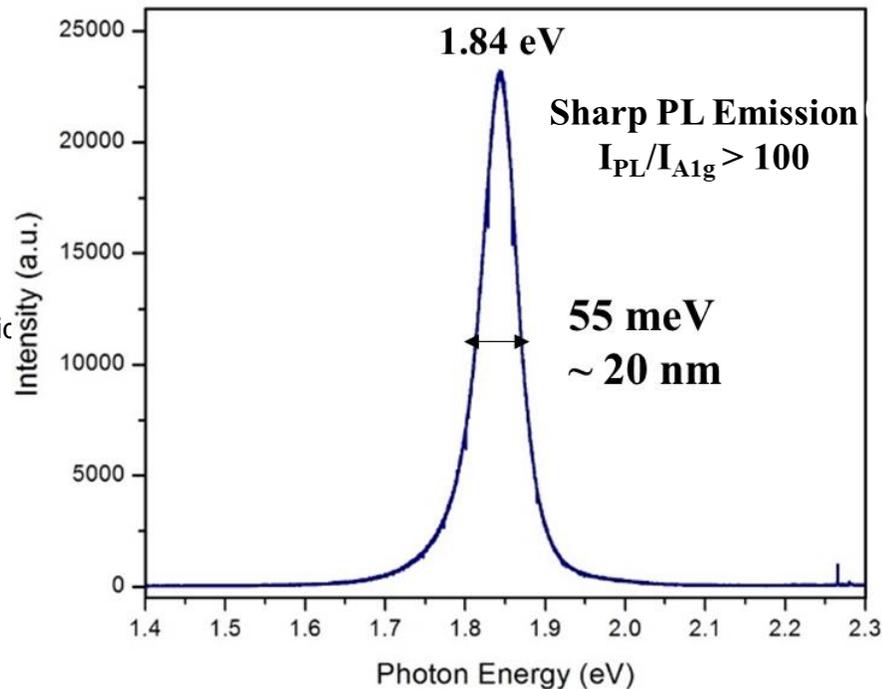


W. Chen et. al, **JACS** 137, 15632 (2015)

Improvement on the synthesis and transfer



perylene-3,4,9,10-tetracarboxylic acid tetrapotassium salt (PTAS)

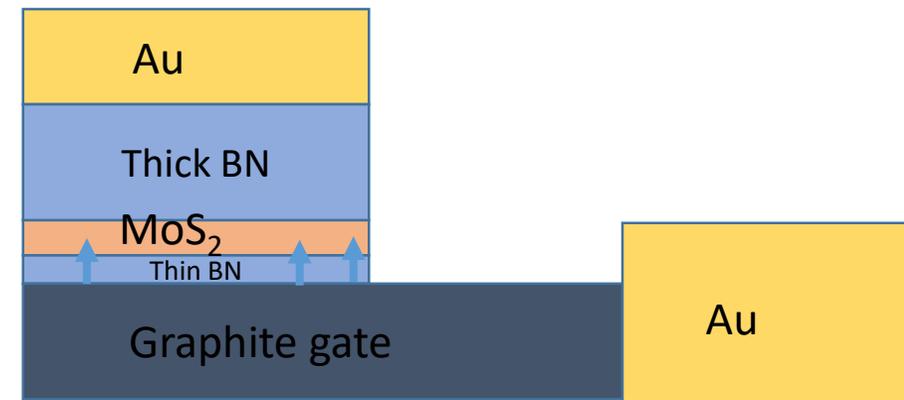
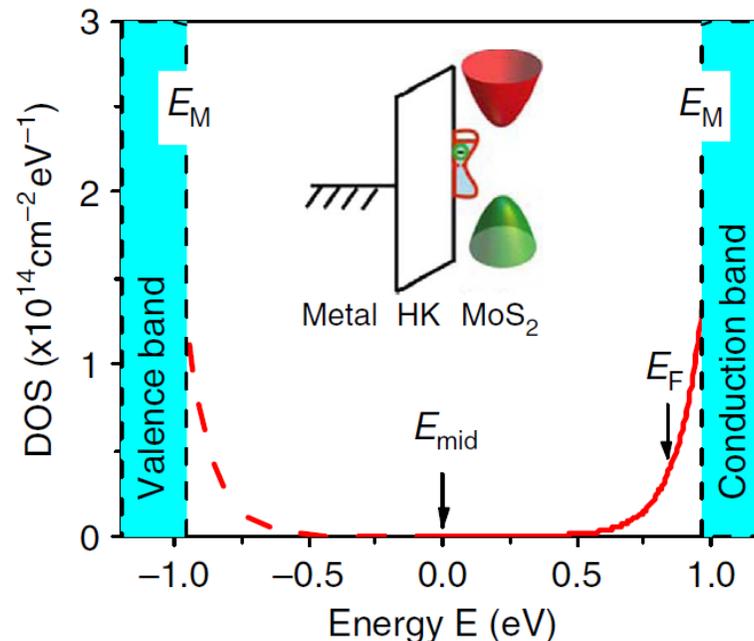
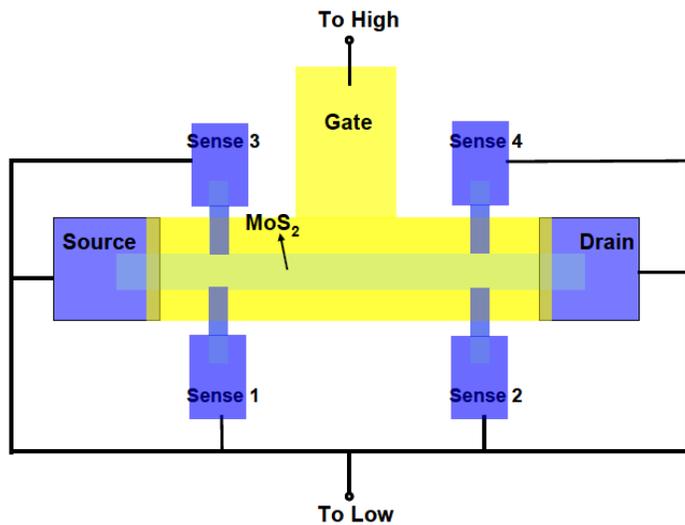


- Simpler PL features instead of PL quantum yield?
- Surface passivation with superacid treatment:
 - Significant impact in optoelectronic applications
 - Effect of passivation on electronic or defect states?

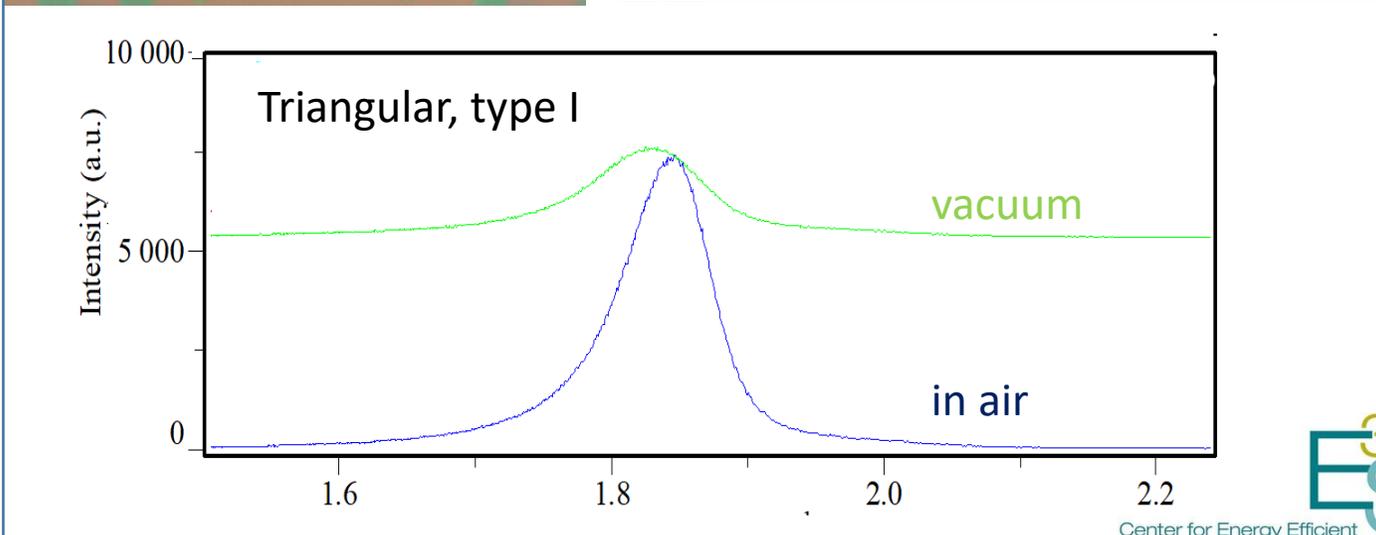
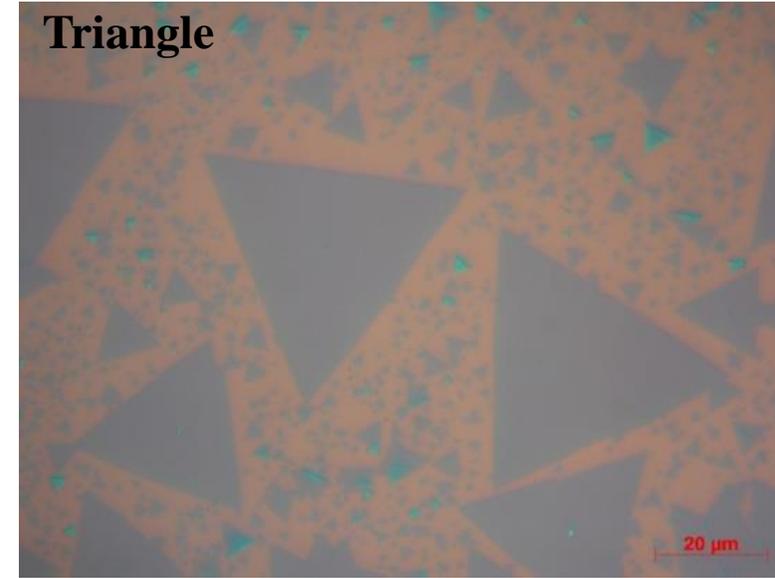
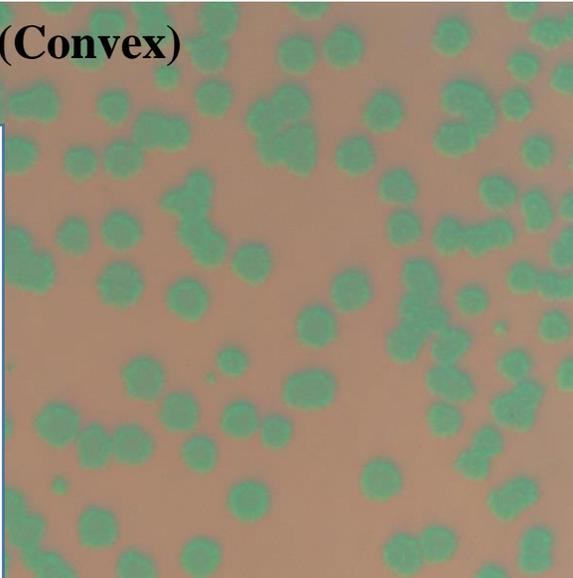
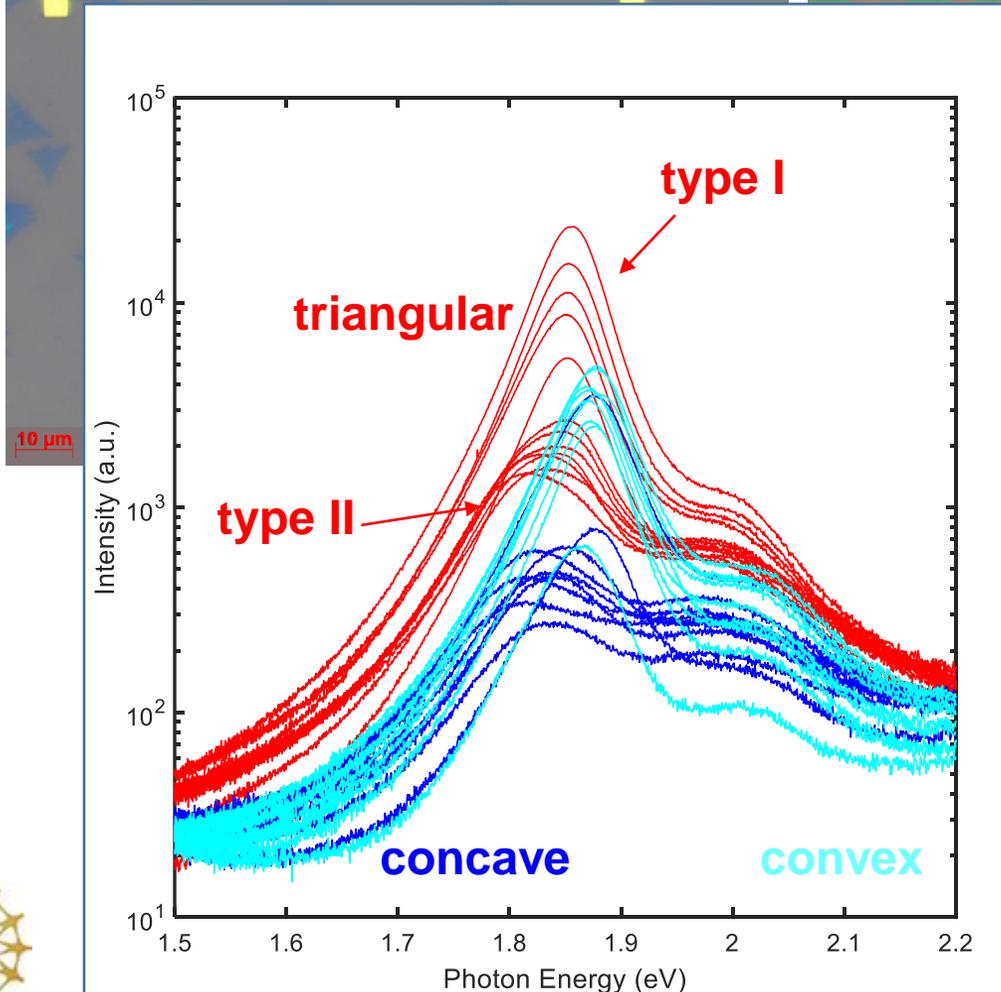
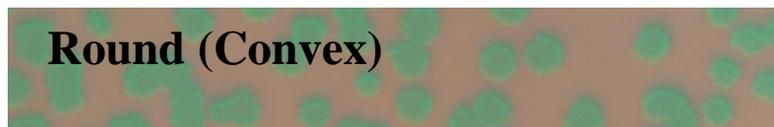
Moving forward: Correlating optical with electrical characterizations



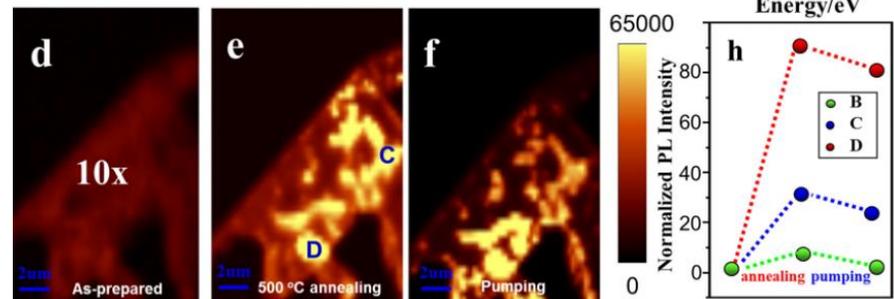
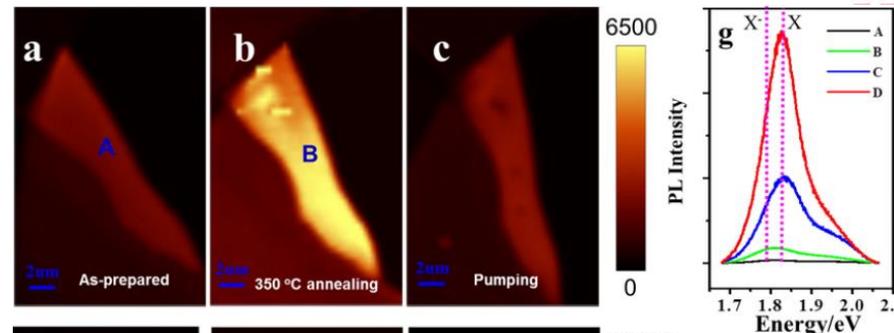
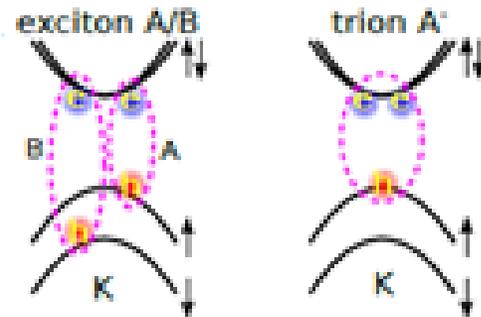
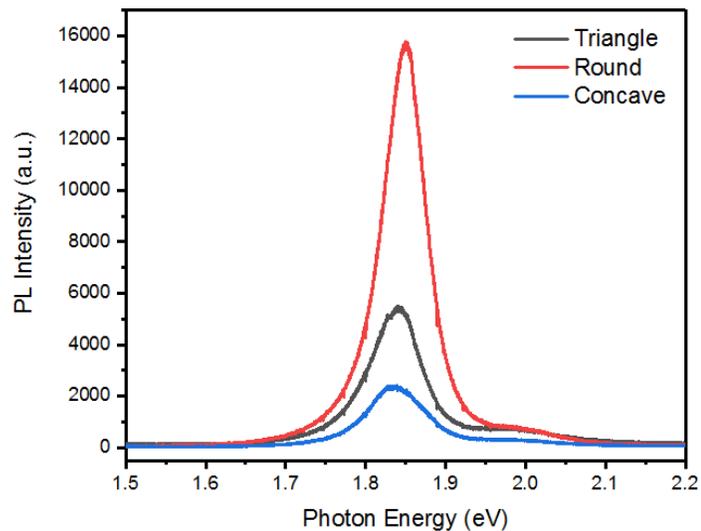
- C-V measurement and device characterizations on MoS₂ with various PL characteristics
 - Superacid treated MoS₂
- Capacitance measurement through “vertical” devices instead of “lateral”: (collaboration with Prof. Ray Ashoori group at MIT)



Optical characterizations with various shapes of MoS₂

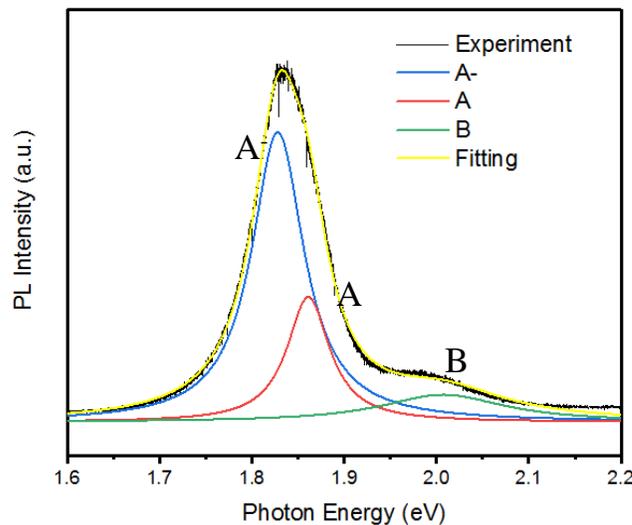


PL Fitting for Exciton and Trion Transitions

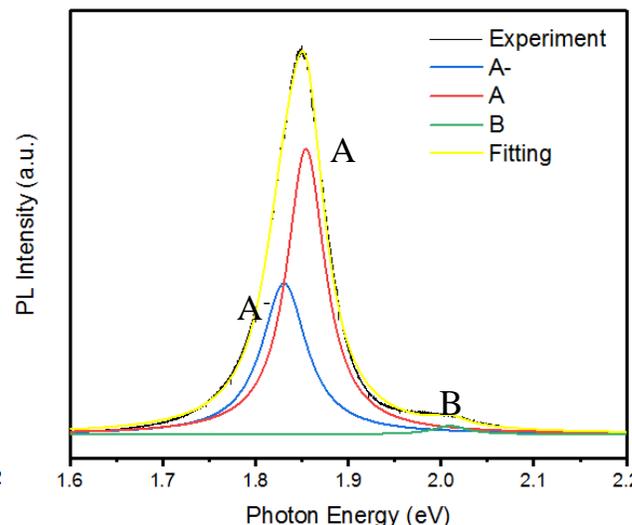


H. Nan et al. *ACS nano* 8.6 (2014): 5738-5745

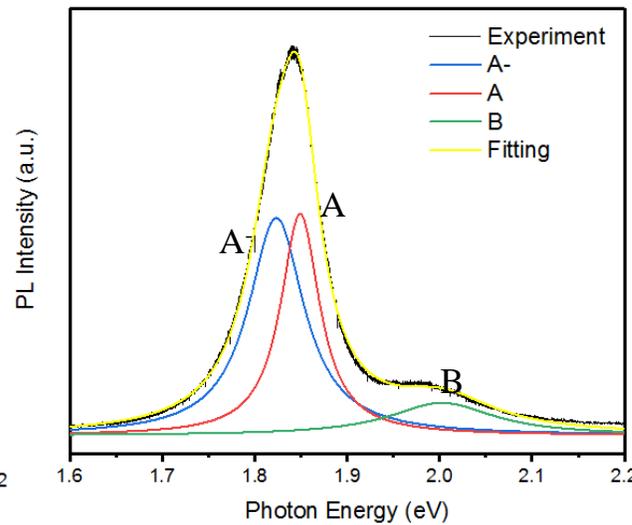
Concave



Round (convex)

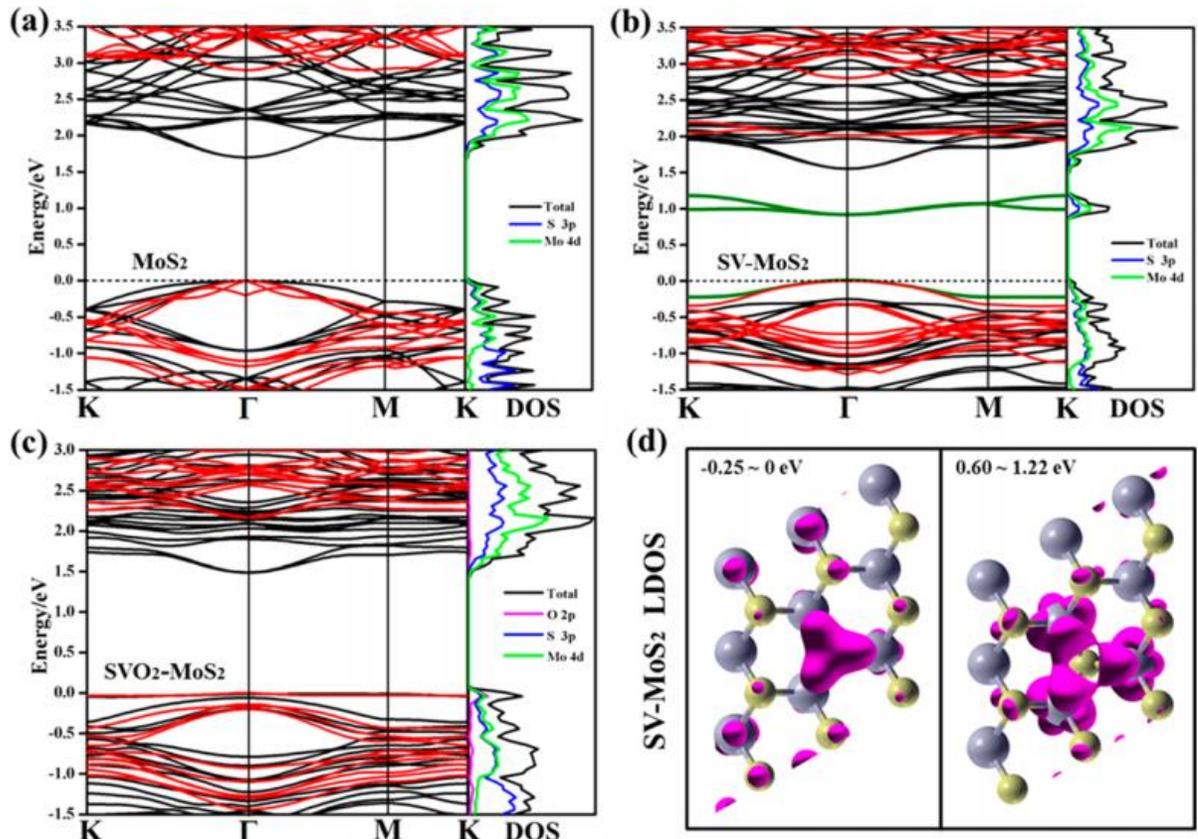


Triangle

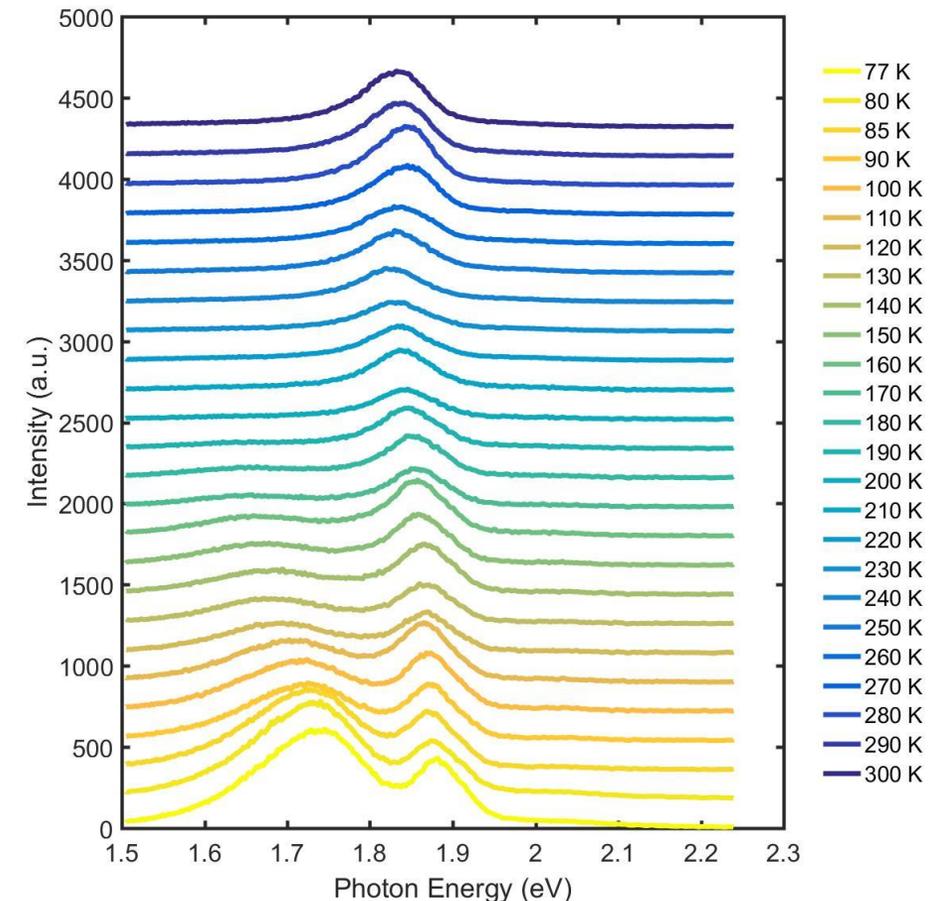


Oxygen passivation and enhanced optical absorption of MoS₂

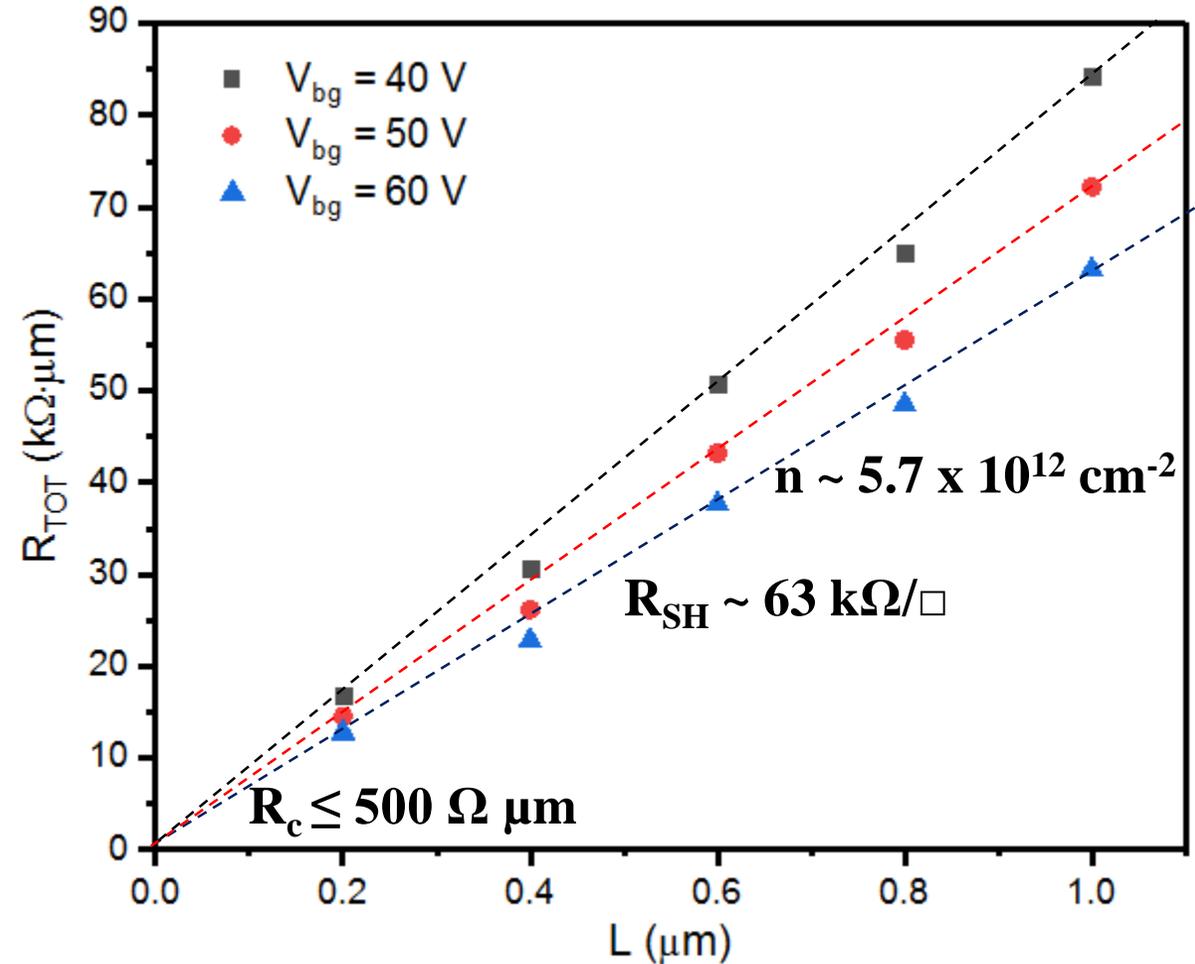
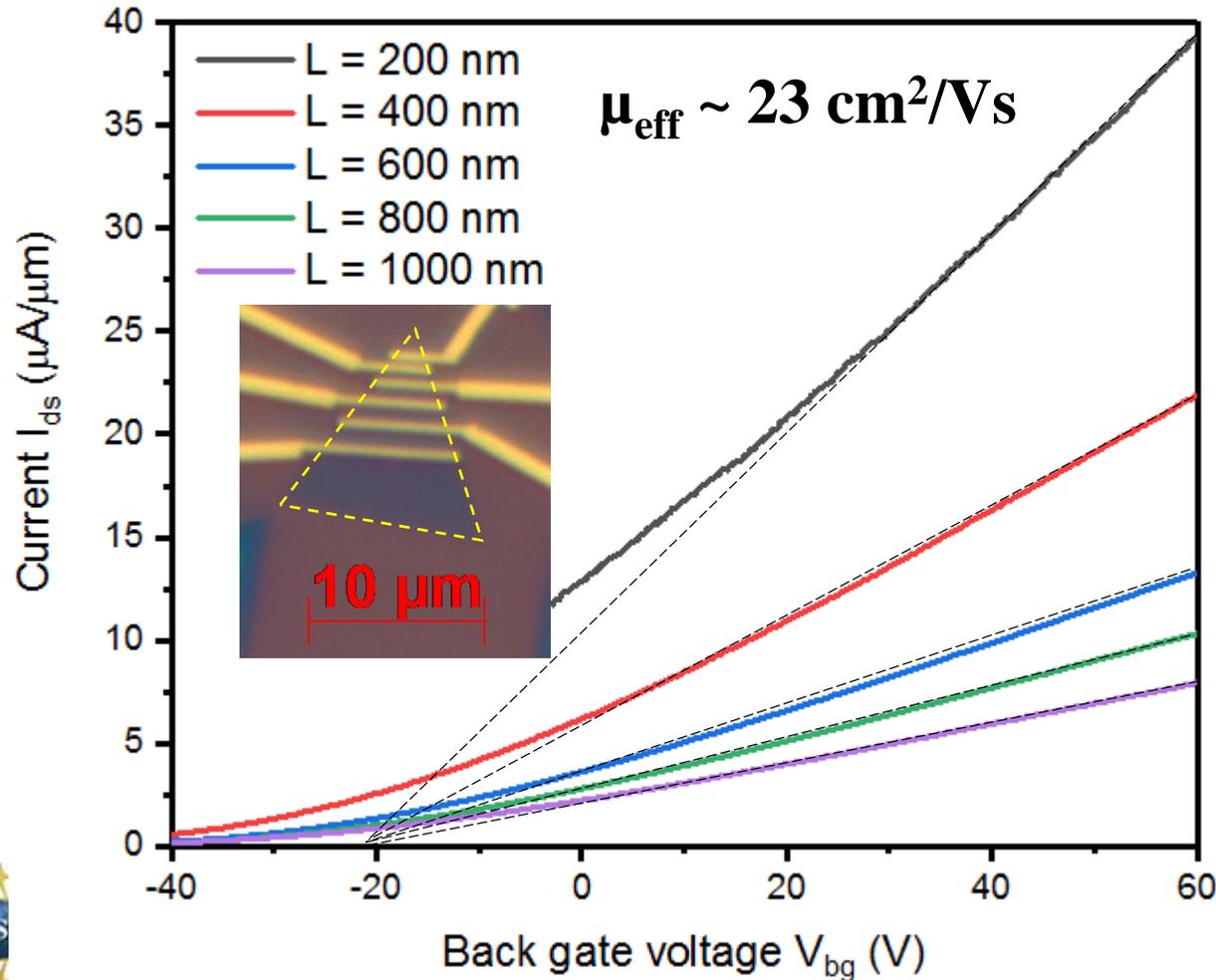
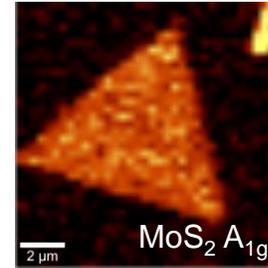
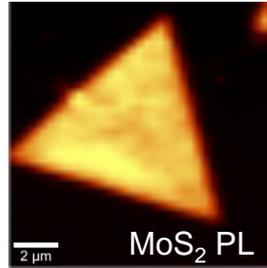
- Sulfur vacancy: one shallow localized state around VBM, two others midgap
- Oxygen passivation: shallow localized state -> a flat “molecular state” 0.015eV above VBM



Triangular type I (convex similar)

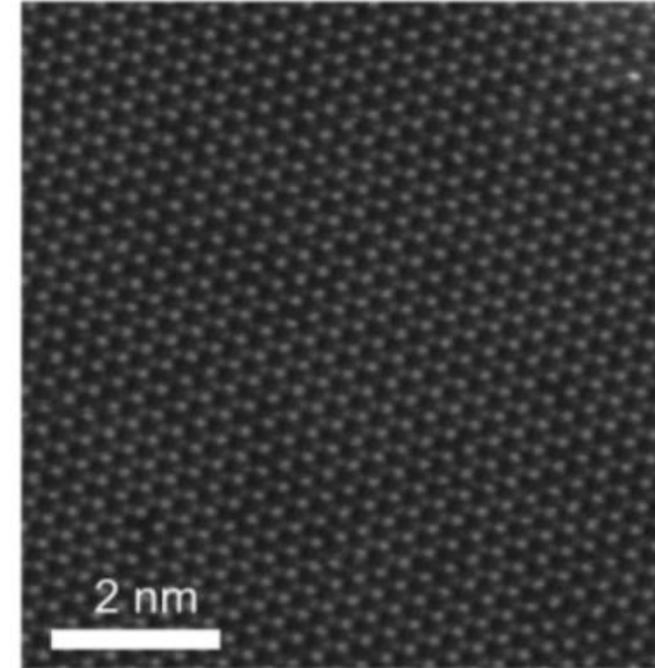
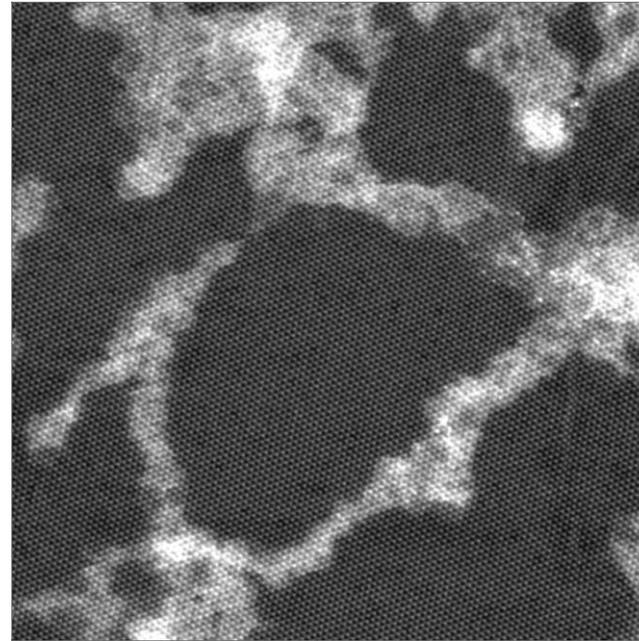
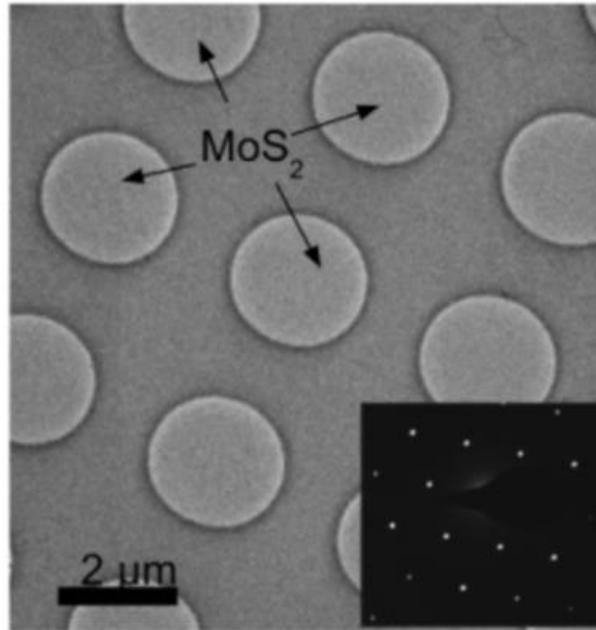


Low-Contact- Resistance Monolayer MoS₂ Transistors

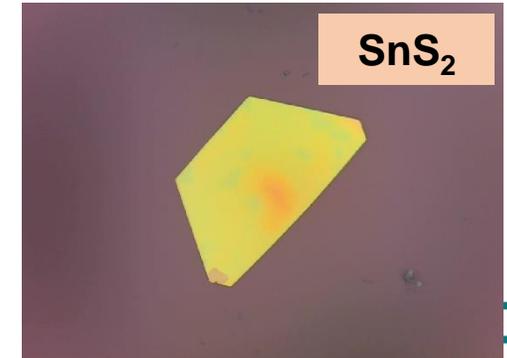
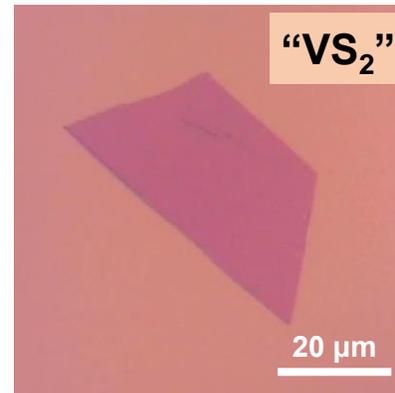
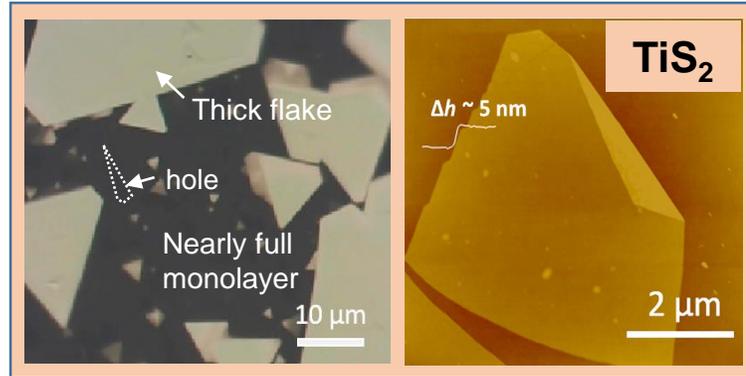
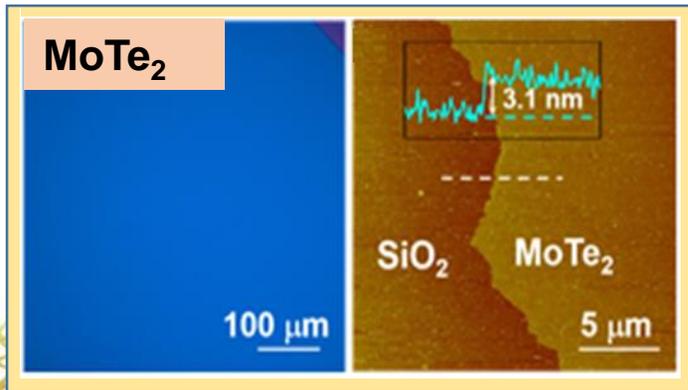
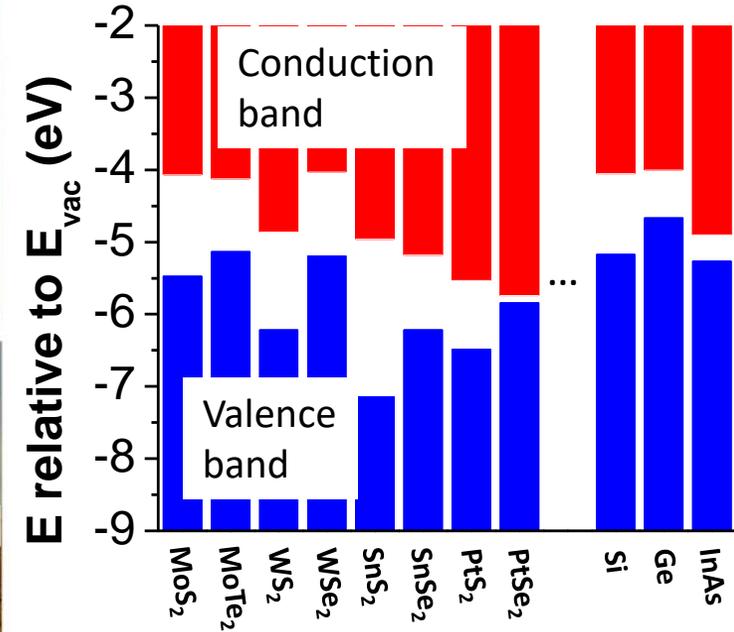
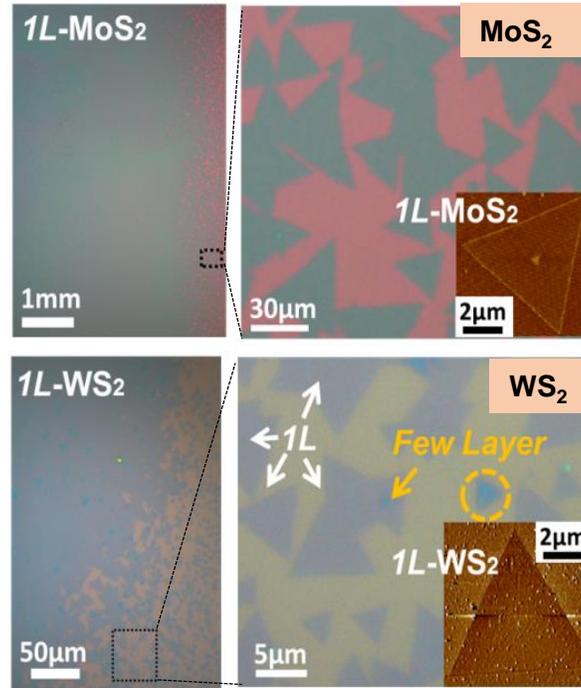
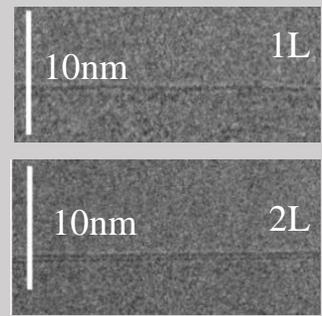
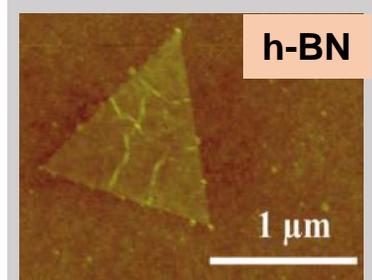
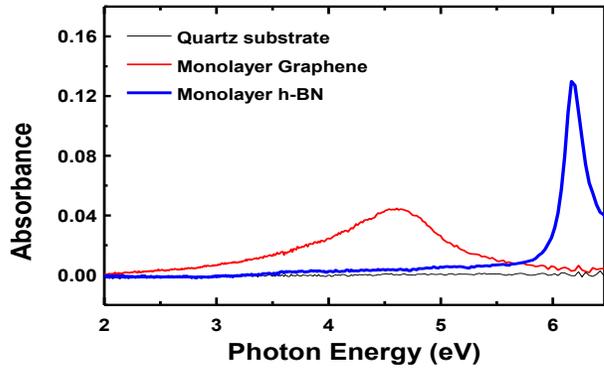


Improvement on the synthesis and transfer

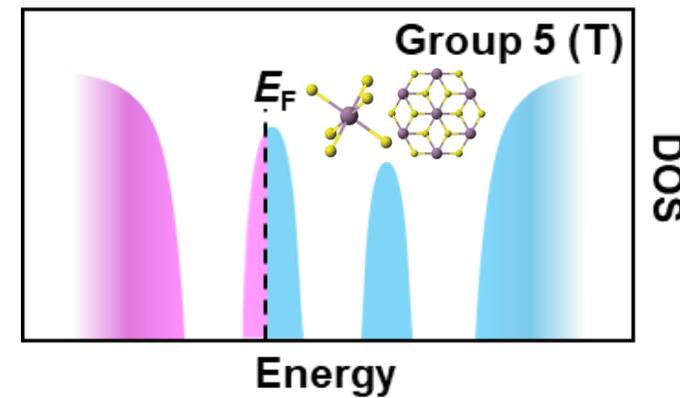
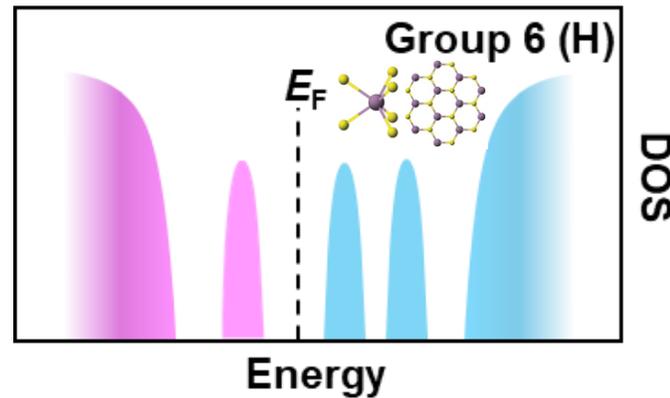
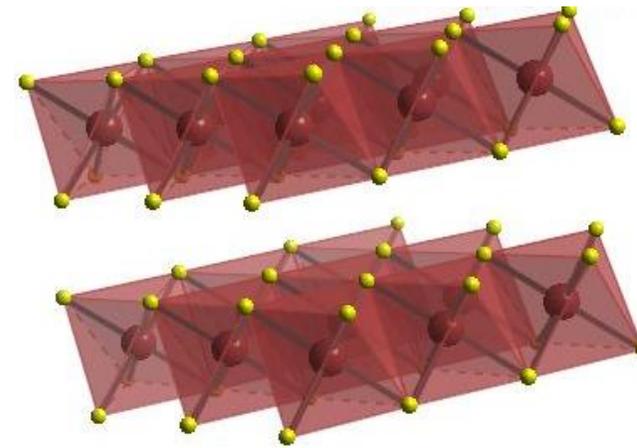
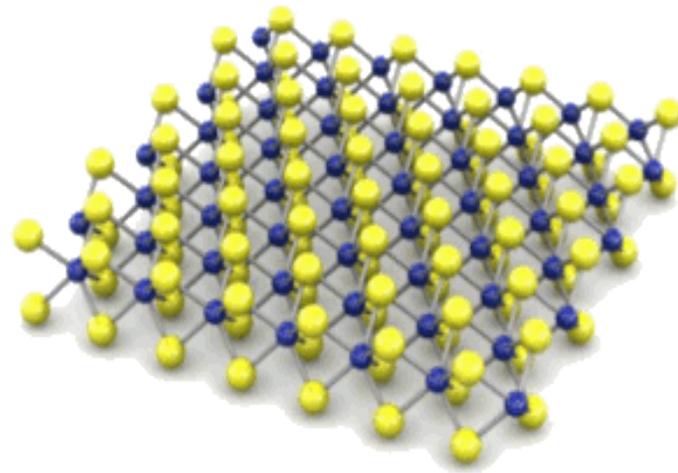
- Clean transfer avoiding polymer residue



Synthesis of other 2D materials

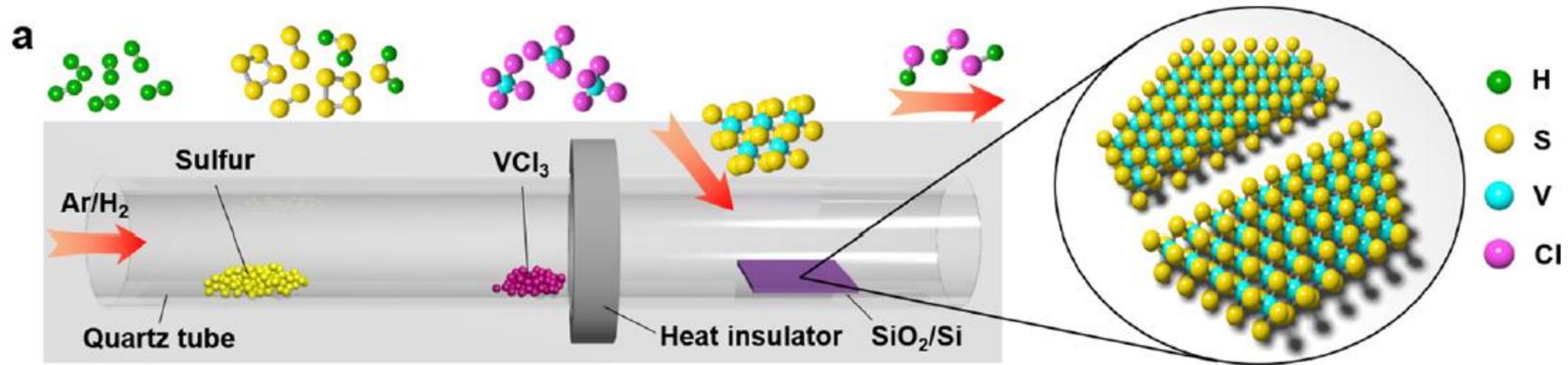


VS₂ vs. MoS₂: similar structures, complementary properties

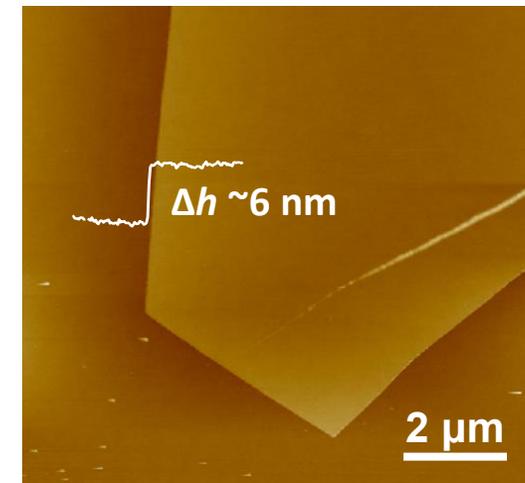
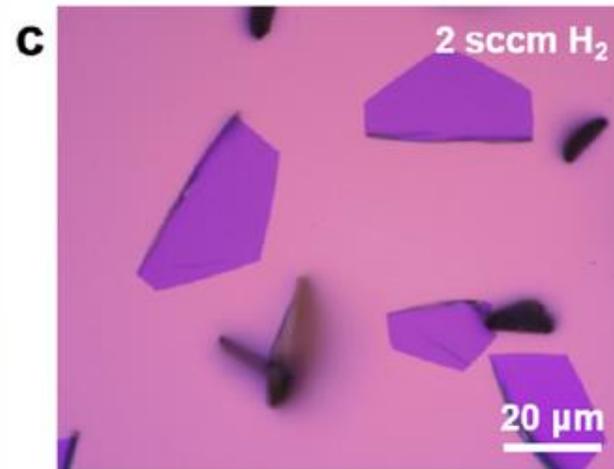
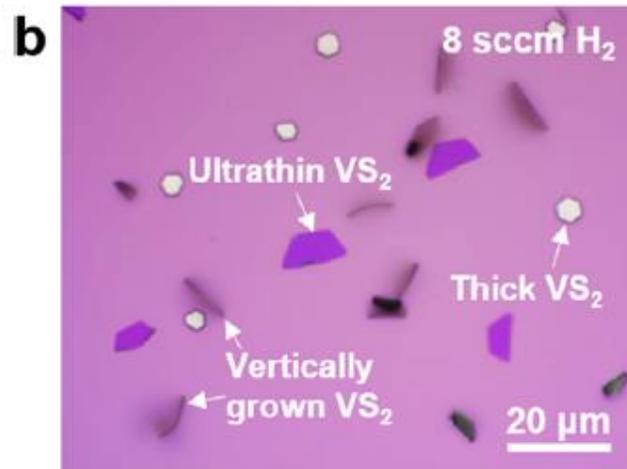
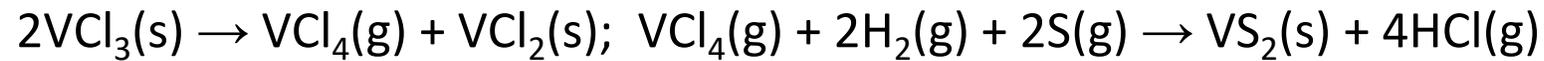


Mater.	Stable phase	periodicity	Layer distance	bandgap
MoS ₂	2H	0.316 nm	0.61 nm	1.8 eV (1L)
VS ₂	1T	0.322 nm	0.58 nm	metal

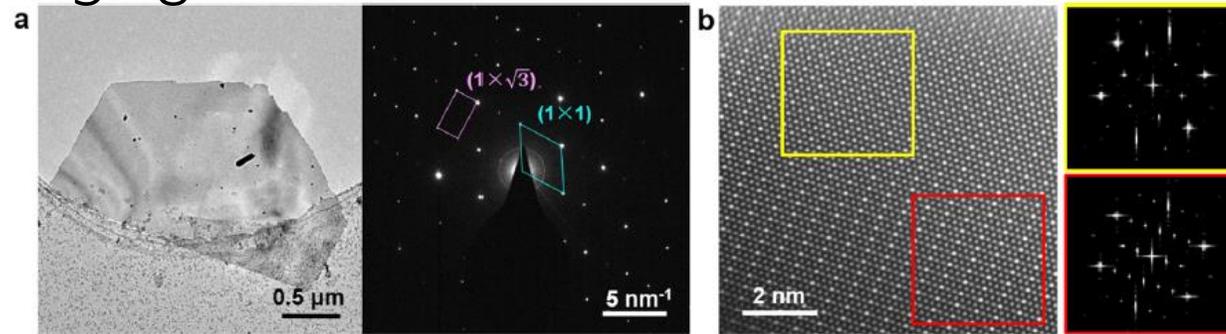
Multilayer "VS₂" flakes



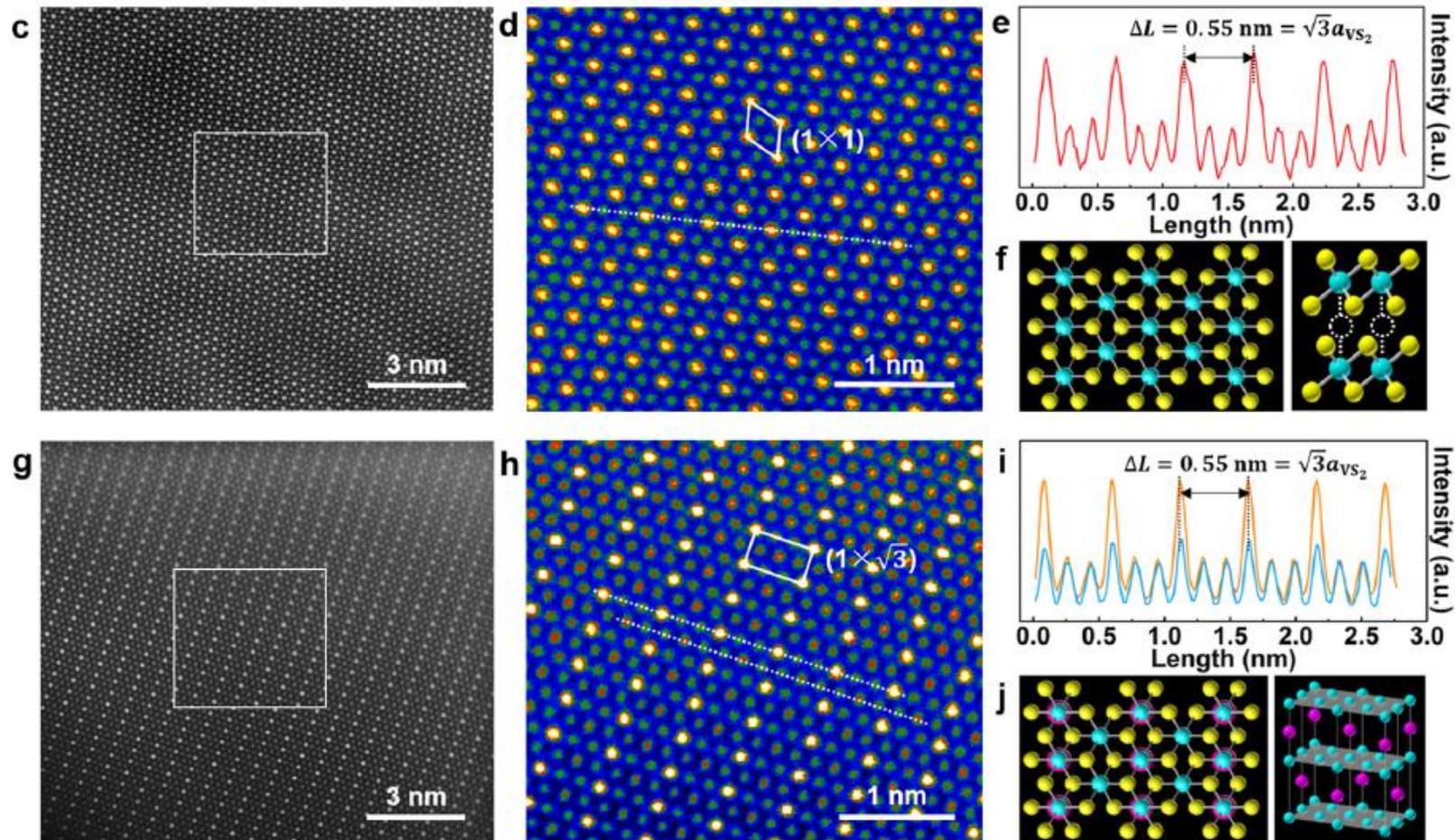
Q. Ji *et al.* *Nano Lett.* **17**, 4908 (2017)



VS₂ and V₅S₈ domains

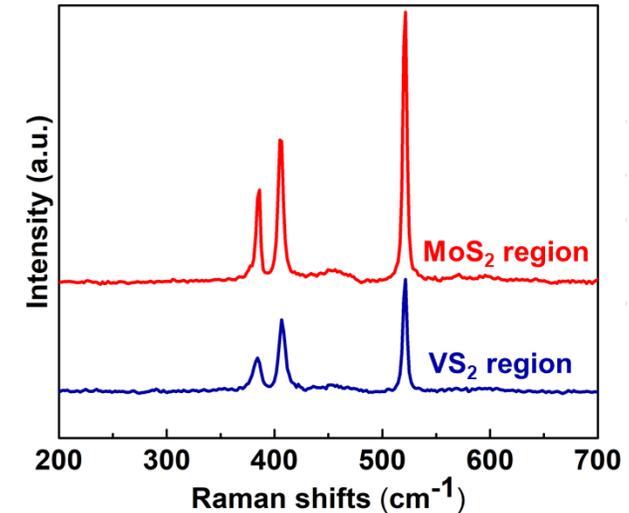
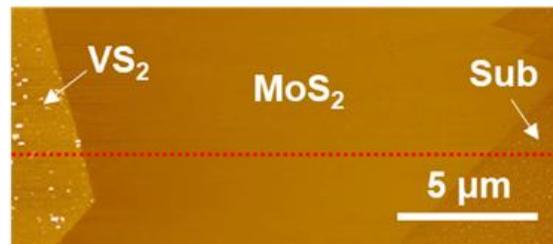
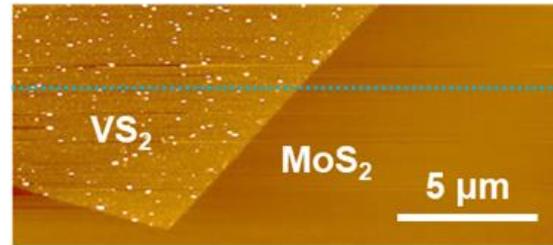
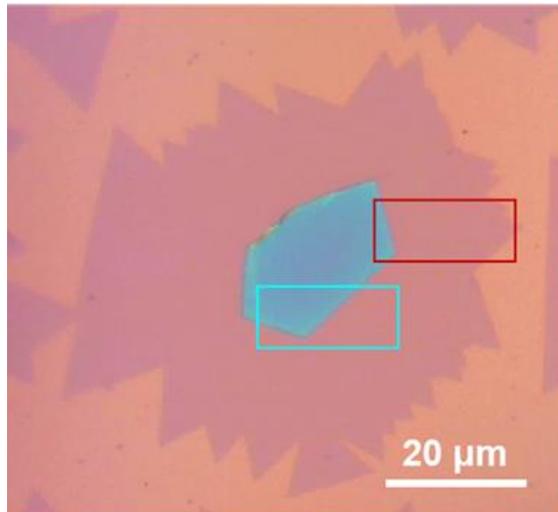
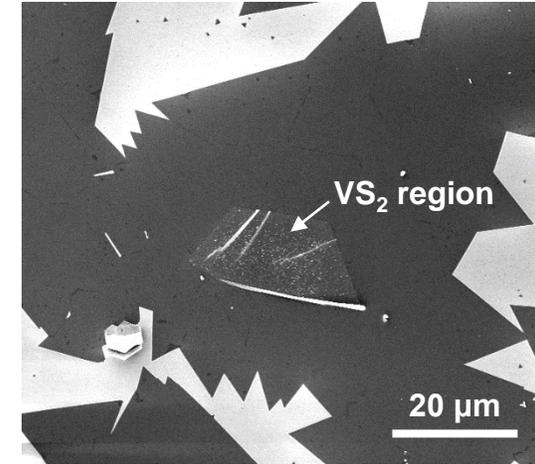
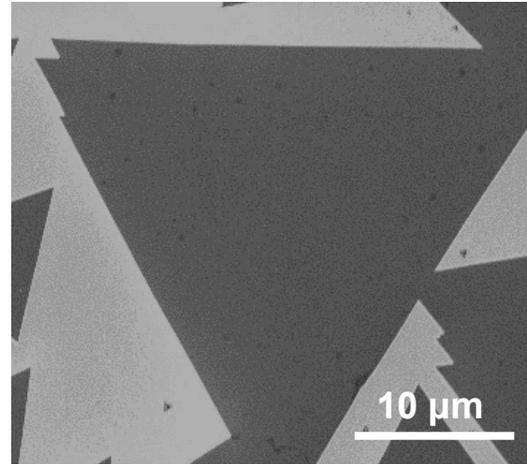
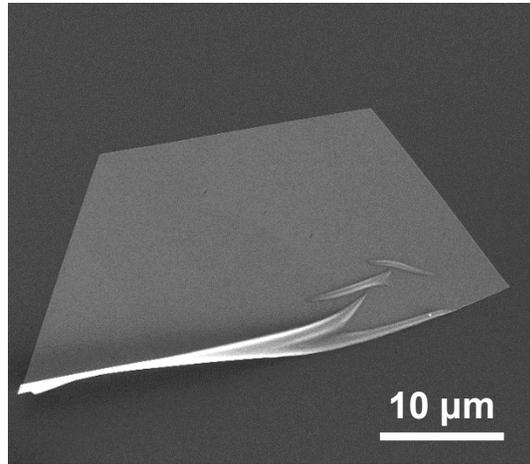


Q. Ji *et al.* *Nano Lett.*
17, 4908 (2017)

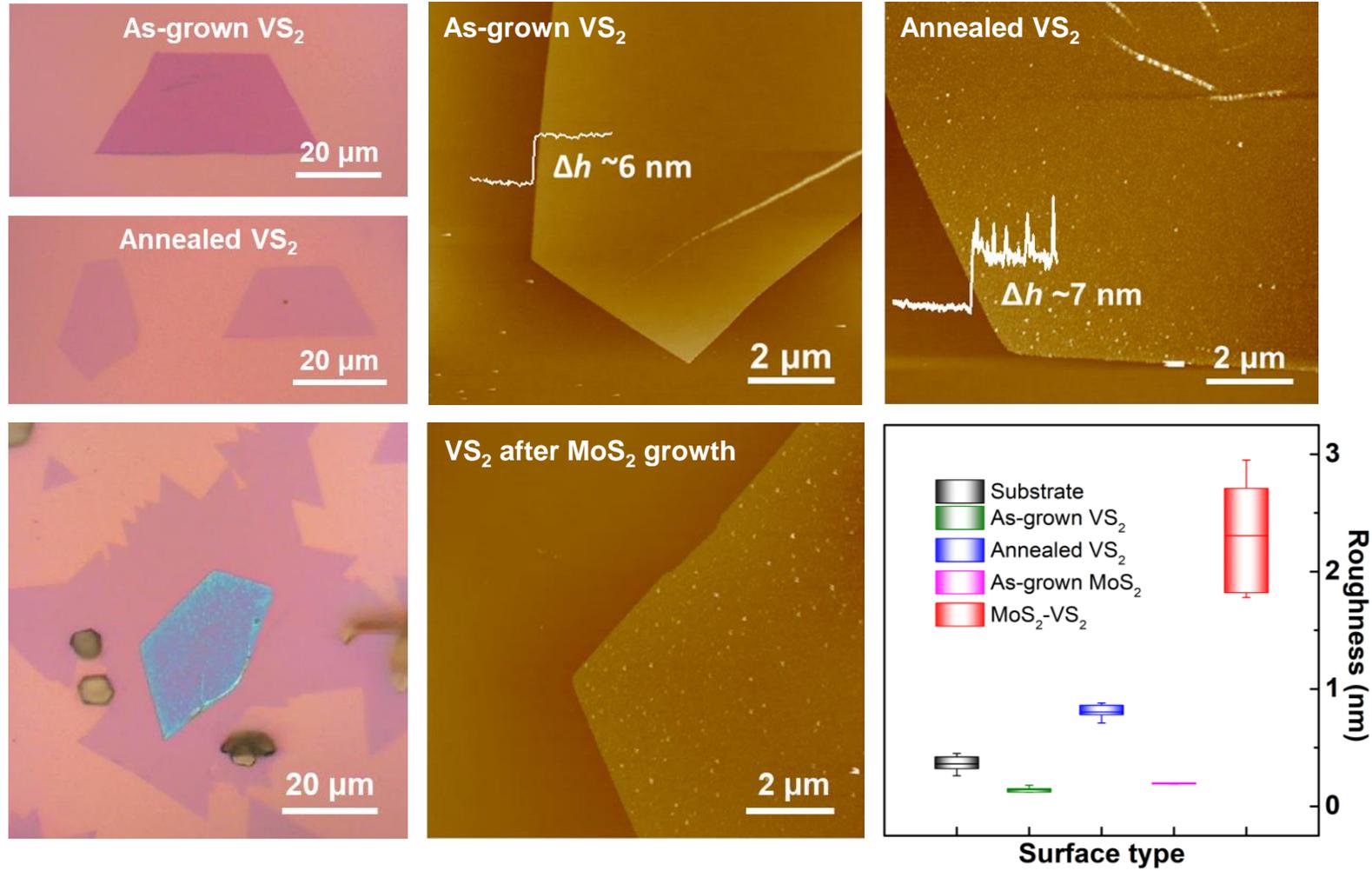


Two step CVD growth for hetero-structure

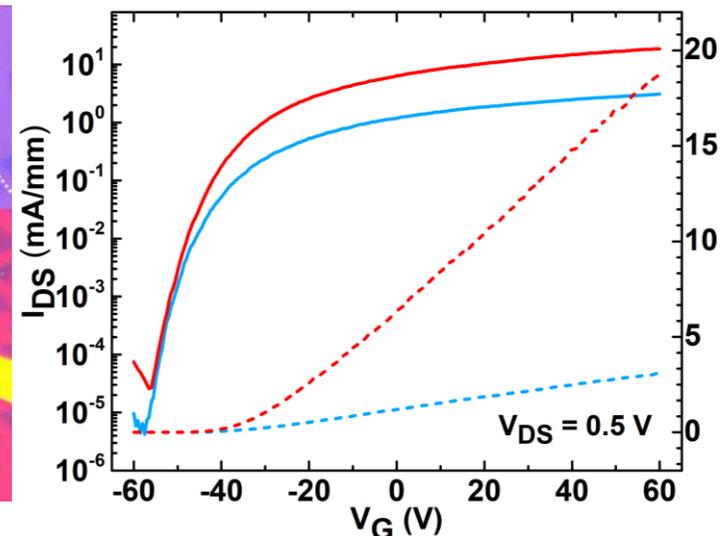
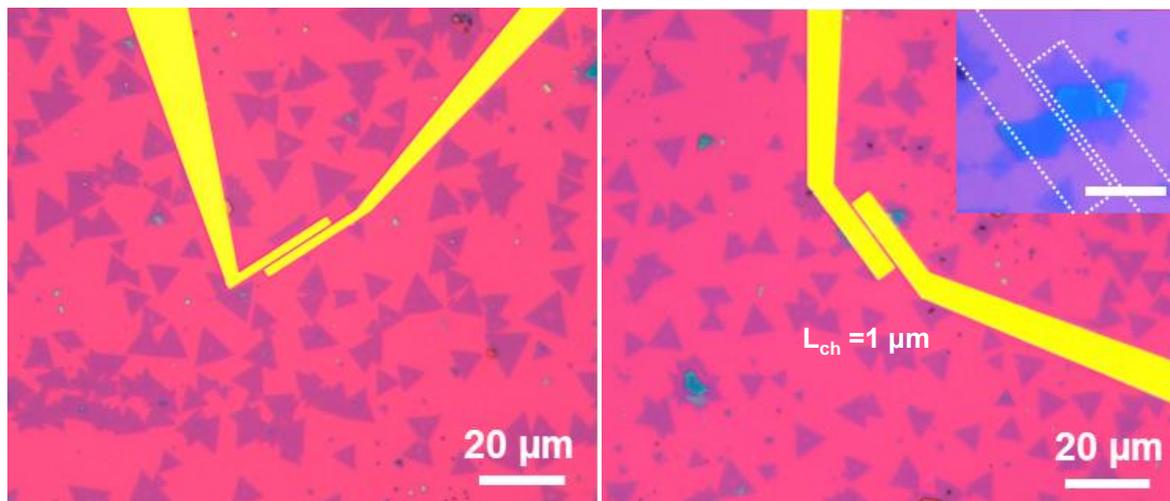
“VS₂” is first grown/transferred, and MoS₂ grows adjacent to “VS₂” flakes



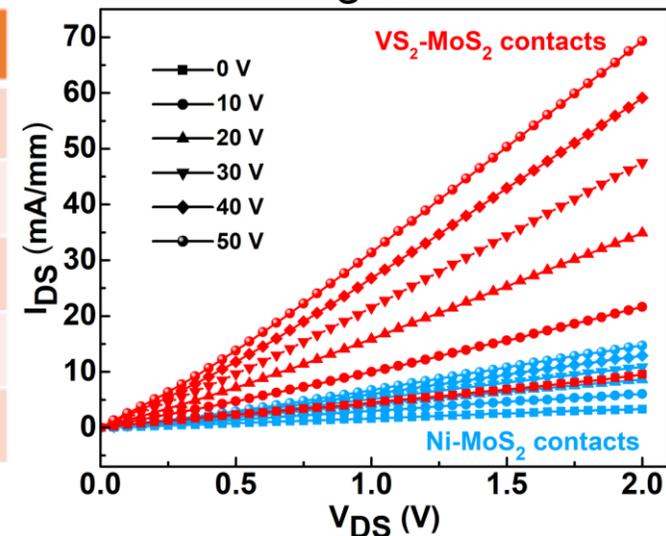
Roughening of the "VS₂" regions



“VS₂” electrical contacts



Properties	Ni contacts	VS ₂ contacts
On currents ($\mu\text{A } \mu\text{m}^{-1}$)	3.0	18.7
Transconductance ($\mu\text{S } \mu\text{m}^{-1}$)	0.033	0.21
Mobility ($\text{cm}^2 \text{V}^{-1} \text{s}^{-1}$)	5.5	35
On/off ratio	$\sim 10^6$	$\sim 10^6$
Subthreshold swing (V dec^{-1})	2.6	2.5



- Preliminary results indicate better contact with “VS₂”

Acknowledgement

- Pin-Chun Shen, Yuxuan Lin, Qingqing Ji, Yunfan Guo, Cong Su, Yimo Han, Wei Sun Leong
- Other Kong group members: Angyu Lu, Jiyuan Zhao, Mahomed Mehdi Goulamaly, Seong Soon Jo, JiHoon Park, Haozhe Wang, Luda Wang, Giovanni Azzellino, Mohammadmahdi Tavakoli, Hongzhang Geng, Luiz Gustavo Pimenta Martins, Nannan Mao, Lin Zhou, Xiaoyan Zhu, Jin Niu, Bingnan Han
- Collaborators: Matin Amani and Ali Javey, Yunan Gao, Aaron Goodman and Prof. William Tisdale, Spencer L. Tomarken and Prof. Ray Ashoori
- Financial Support:
 - E3S center
 - Excitonics Center via DOE, Basic Energy Sciences
 - Center for Integrated Quantum Materials (CIQM) from NSF grant DMR-1231319
 - MIT Lincoln Lab Advanced Concept Committee
 - Eni-MIT Alliance Solar Frontiers Center
 - ISN at MIT
 - AFSOR MURI



HKUST-MIT Alliance



Thank you very much!